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                                                    * * * * * * * * * *
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                 Web Page for STN Seminar Schedule - N. America
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         AUG 06
                 CAS REGISTRY enhanced with new experimental property tags
NEWS
         AUG 06
                 FSTA enhanced with new thesaurus edition
NEWS 4
         AUG 13
                 CA/CAplus enhanced with additional kind codes for granted
                 patents
NEWS
         AUG 20
                 CA/CAplus enhanced with CAS indexing in pre-1907 records
NEWS
         AUG 27
                 Full-text patent databases enhanced with predefined
                 patent family display formats from INPADOCDB
NEWS
      7 AUG 27
                 USPATOLD now available on STN
NEWS 8 AUG 28
                 CAS REGISTRY enhanced with additional experimental
                 spectral property data
NEWS 9 SEP 07
                 STN AnaVist, Version 2.0, now available with Derwent
                 World Patents Index
NEWS 10 SEP 13
                 FORIS renamed to SOFIS
NEWS 11 SEP 13
                 INPADOCDB enhanced with monthly SDI frequency
NEWS 12
         SEP 17
                 CA/CAplus enhanced with printed CA page images from
                 1967-1998
NEWS 13
         SEP 17 CAplus coverage extended to include traditional medicine
                 patents
NEWS 14 SEP 24
                 EMBASE, EMBAL, and LEMBASE reloaded with enhancements
NEWS 15 OCT 02 CA/Caplus enhanced with pre-1907 records from Chemisches
                 Zentralblatt
NEWS 16 OCT 19 BEILSTEIN updated with new compounds
NEWS 17 NOV 15 Derwent Indian patent publication number format enhanced
NEWS 18 NOV 19 WPIX enhanced with XML display format
NEWS 19 NOV 30 ICSD reloaded with enhancements
NEWS 20 DEC 04 LINPADOCDB now available on STN
NEWS 21 DEC 14 BEILSTEIN pricing structure to change
NEWS 22 DEC 17 USPATOLD added to additional database clusters
NEWS 23
         DEC 17 IMSDRUGCONF removed from database clusters and STN
         DEC 17 DGENE now includes more than 10 million sequences
NEWS 24
         DEC 17 TOXCENTER enhanced with 2008 MeSH vocabulary in
NEWS 25
                 MEDLINE segment
         DEC 17
NEWS 26
                 MEDLINE and LMEDLINE updated with 2008 MeSH vocabulary
NEWS 27
         DEC 17
                 CA/CAplus enhanced with new custom IPC display formats
NEWS 28
         DEC 17
                 STN Viewer enhanced with full-text patent content
                 from USPATOLD
NEWS 29
         JAN 02
                 STN pricing information for 2008 now available
NEWS 30
         JAN 16
                 CAS patent coverage enhanced to include exemplified
```

prophetic substances

NEWS 31 JAN 28 USPATFULL, USPAT2, and USPATOLD enhanced with new custom IPC display formats

NEWS 32 JAN 28 MARPAT searching enhanced

NEWS 33 JAN 28 USGENE now provides USPTO sequence data within 3 days of publication

NEWS 34 JAN 28 TOXCENTER enhanced with reloaded MEDLINE segment

NEWS 35 JAN 28 MEDLINE and LMEDLINE reloaded with enhancements

NEWS 36 FEB 08 STN Express, Version 8.3, now available

NEWS EXPRESS FEBRUARY 08 CURRENT WINDOWS VERSION IS V8.3,
AND CURRENT DISCOVER FILE IS DATED 24 JANUARY 2008

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=> file reg

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FULL ESTIMATED COST
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0.21

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STRUCTURE FILE UPDATES: 13 FEB 2008 HIGHEST RN 1003293-96-6 DICTIONARY FILE UPDATES: 13 FEB 2008 HIGHEST RN 1003293-96-6

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http://www.cas.org/support/stngen/stndoc/properties.html

=> s 42459-51-8 L1 1 42459-51-8 (42459-51-8/RN)

=> d

L1 ANSWER 1 OF 1 REGISTRY COPYRIGHT 2008 ACS on STN

RN 42459-51-8 REGISTRY

ED Entered STN: 16 Nov 1984

CN Tricyclo[3.3.1.13,7]decane, 1-(ethenyloxy)- (CA INDEX NAME)

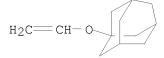
OTHER NAMES:

CN 1-Adamantyl vinyl ether

MF C12 H18 O

CI COM

LC STN Files: CA, CAPLUS, CASREACT, USPAT2, USPATFULL



PROPERTY DATA AVAILABLE IN THE 'PROP' FORMAT

11 REFERENCES IN FILE CA (1907 TO DATE)

2 REFERENCES TO NON-SPECIFIC DERIVATIVES IN FILE CA

11 REFERENCES IN FILE CAPLUS (1907 TO DATE)

=> s adamantol

L2 3 ADAMANTOL

=> d 1-3

L2 ANSWER 1 OF 3 REGISTRY COPYRIGHT 2008 ACS on STN

RN 58652-35-0 REGISTRY

ED Entered STN: 16 Nov 1984

CN Tricyclo[3.3.1.13,7]decan-1-ol, 3-fluoro- (CA INDEX NAME)

OTHER NAMES:

CN 3-Fluoro-1-adamantol

CN 3-Fluoroadamantan-1-ol

MF C10 H15 F O

LC STN Files: BEILSTEIN*, CA, CAPLUS, CASREACT, IFICDB, IFIPAT, IFIUDB, USPATFULL

(*File contains numerically searchable property data)



PROPERTY DATA AVAILABLE IN THE 'PROP' FORMAT

10 REFERENCES IN FILE CA (1907 TO DATE)

10 REFERENCES IN FILE CAPLUS (1907 TO DATE)

L2 ANSWER 2 OF 3 REGISTRY COPYRIGHT 2008 ACS on STN

RN 16269-10-6 REGISTRY

ED Entered STN: 16 Nov 1984

CN Tricyclo[3.3.1.13,7]decane-1-carboxylic acid,

tricyclo[3.3.1.13,7]dec-1-yl

ester (CA INDEX NAME)

OTHER CA INDEX NAMES:

CN 1-Adamantanecarboxylic acid, 1-adamantyl ester (8CI)

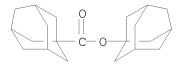
CN 1-Adamantol, 1-adamantanecarboxylate

OTHER NAMES:

CN 1-Adamantyl 1-adamantanecarboxylate

MF C21 H30 O2

LC STN Files: BEILSTEIN*, CA, CAPLUS, CASREACT, CHEMCATS (*File contains numerically searchable property data)



PROPERTY DATA AVAILABLE IN THE 'PROP' FORMAT

4 REFERENCES IN FILE CA (1907 TO DATE)

4 REFERENCES IN FILE CAPLUS (1907 TO DATE)

L2 ANSWER 3 OF 3 REGISTRY COPYRIGHT 2008 ACS on STN

RN 15215-43-7 REGISTRY

ED Entered STN: 16 Nov 1984

CN Cyclohexanecarbamic acid, 1-adamantyl ester (8CI) (CA INDEX NAME) OTHER CA INDEX NAMES:

CN 1-Adamantanol, cyclohexanecarbamate

CN 1-Adamantol, cyclohexanecarbamate

MF C17 H27 N O2

LC STN Files: BEILSTEIN*, CA, CAPLUS, CHEMCATS (*File contains numerically searchable property data)

PROPERTY DATA AVAILABLE IN THE 'PROP' FORMAT

2 REFERENCES IN FILE CA (1907 TO DATE)

2 REFERENCES IN FILE CAPLUS (1907 TO DATE)

=> s adamant and ol

4685 ADAMANT

5153545 OL

L3 564 ADAMANT AND OL

=> s 13

4685 ADAMANT

5153545 OL

L4 564 ADAMANT AND OL

=> d 564

L4 ANSWER 564 OF 564 REGISTRY COPYRIGHT 2008 ACS on STN

RN 665-66-7 REGISTRY

ED Entered STN: 16 Nov 1984

CN Tricyclo[3.3.1.13,7]decan-1-amine, hydrochloride (1:1) (CA INDEX NAME)

OTHER CA INDEX NAMES:

CN 1-Adamantanamine, hydrochloride (8CI)

CN Adamantanamine hydrochloride (6CI)

CN Tricyclo[3.3.1.13,7]decan-1-amine, hydrochloride (9CI)

OTHER NAMES:

CN 1-Adamantamine hydrochloride

CN 1-Adamantylamine hydrochloride

CN 1-Aminoadamantane hydrochloride

CN Adamantylamine hydrochloride

CN Adamin

CN Adamine

CN Amantadine hydrochloride

CN Amazolon

CN Aminoadamantane hydrochloride

CN EXP 105-1

CN Mantadan

CN Mantadine

CN Mantadix

CN Midantan

CN Midantane

CN Mydantane CN NSC 83653

CN Symadine

CN Symmetrel

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CN
    Virasol
CN
    Virofral
MF
    C10 H17 N . Cl H
CI
     STN Files: ADISINSIGHT, ADISNEWS, AGRICOLA, ANABSTR, BEILSTEIN*,
LC
BIOSIS,
       BIOTECHNO, CA, CAOLD, CAPLUS, CASREACT, CBNB, CHEMCATS, CHEMLIST, CIN,
       CSCHEM, EMBASE, HSDB*, IFICDB, IFIPAT, IFIUDB, IMSRESEARCH, IPA,
       MEDLINE, MRCK*, PIRA, PROMT, PROUSDDR, PS, RTECS*, SCISEARCH, SPECINFO,
       TOXCENTER, USAN, USPAT2, USPATFULL, USPATOLD
         (*File contains numerically searchable property data)
     Other Sources: EINECS**, NDSL**, TSCA**
         (**Enter CHEMLIST File for up-to-date regulatory information)
CRN (768-94-5)
   HC1
**PROPERTY DATA AVAILABLE IN THE 'PROP' FORMAT**
             669 REFERENCES IN FILE CA (1907 TO DATE)
               4 REFERENCES TO NON-SPECIFIC DERIVATIVES IN FILE CA
             671 REFERENCES IN FILE CAPLUS (1907 TO DATE)
              18 REFERENCES IN FILE CAOLD (PRIOR TO 1967)
=> s adamant adj 1 adj ol
          4685 ADAMANT
           184 ADJ
      22654369 1
           184 ADJ
       5153545 OL
             0 ADAMANT ADJ 1 ADJ OL
L_5
                 (ADAMANT (W) ADJ (W) 1 (W) ADJ (W) OL)
=> s adamant and ol
          4685 ADAMANT
       5153545 OL
           564 ADAMANT AND OL
L6
=> s C10H16o/mfw
'MFW' IS NOT A VALID FIELD CODE
             0 C10H16O/MFW
```

=> s C10H16o/mf

FOR 10/553083 by Cynthia Hamilton 5733 C10H16O/MF L8 => s 18 and 16 2 L8 AND L6 L9 => d 1-2L9 ANSWER 1 OF 2 REGISTRY COPYRIGHT 2008 ACS on STN 96929-65-6 REGISTRY ED Entered STN: 01 Jul 1985 CN 2,5-Methano-1H-inden-7a(2H)-ol, hexahydro- (9CI) (CA INDEX NAME) OTHER NAMES: 3-Protoadamantyl alcohol CN CN 6-Protoadamantanol MF C10 H16 O LC STN Files: BEILSTEIN*, CA, CAPLUS, CASREACT, TOXCENTER (*File contains numerically searchable property data) ОН **PROPERTY DATA AVAILABLE IN THE 'PROP' FORMAT** 6 REFERENCES IN FILE CA (1907 TO DATE) 6 REFERENCES IN FILE CAPLUS (1907 TO DATE) L9 ANSWER 2 OF 2 REGISTRY COPYRIGHT 2008 ACS on STN 768-95-6 REGISTRY RN Entered STN: 16 Nov 1984 Tricyclo[3.3.1.13,7]decan-1-ol (CA INDEX NAME) OTHER CA INDEX NAMES: CN 1-Adamantanol (6CI, 7CI, 8CI) OTHER NAMES: 1-Adamantyl alcohol CN CN 1-Hydroxyadamantane CN NSC 108837 CN NSC 91633 C10 H16 O MFCI COM LC ANABSTR, BEILSTEIN*, BIOSIS, CA, CAOLD, CAPLUS, CASREACT, CHEMCATS, CHEMINFORMRX, CHEMLIST, CSCHEM, DETHERM*, EMBASE, GMELIN*, IFICDB, IFIPAT, IFIUDB, MSDS-OHS, RTECS*, SPECINFO, SYNTHLINE, TOXCENTER, USPAT2, USPATFULL, USPATOLD

(*File contains numerically searchable property data)

(**Enter CHEMLIST File for up-to-date regulatory information)

EINECS**

Other Sources:



PROPERTY DATA AVAILABLE IN THE 'PROP' FORMAT 1644 REFERENCES IN FILE CA (1907 TO DATE)

21 REFERENCES TO NON-SPECIFIC DERIVATIVES IN FILE CA 1652 REFERENCES IN FILE CAPLUS (1907 TO DATE)

11 REFERENCES IN FILE CAOLD (PRIOR TO 1967)

=> s 768-95-61 768-95-6 L10(768-95-6/RN)

=> d

L10 ANSWER 1 OF 1 REGISTRY COPYRIGHT 2008 ACS on STN

768-95-6 REGISTRY

Entered STN: 16 Nov 1984

Tricyclo[3.3.1.13,7]decan-1-ol (CA INDEX NAME)

OTHER CA INDEX NAMES:

1-Adamantanol (6CI, 7CI, 8CI) CN

OTHER NAMES:

CN 1-Adamantyl alcohol 1-Hydroxyadamantane CN

NSC 108837 CN

CN NSC 91633

MF C10 H16 O

CI COM

LC ANABSTR, BEILSTEIN*, BIOSIS, CA, CAOLD, CAPLUS, CASREACT, CHEMCATS, CHEMINFORMRX, CHEMLIST, CSCHEM, DETHERM*, EMBASE, GMELIN*, IFICDB, IFIPAT, IFIUDB, MSDS-OHS, RTECS*, SPECINFO, SYNTHLINE, TOXCENTER, USPAT2, USPATFULL, USPATOLD

(*File contains numerically searchable property data) Other Sources: EINECS**

(**Enter CHEMLIST File for up-to-date regulatory information)



PROPERTY DATA AVAILABLE IN THE 'PROP' FORMAT

1644 REFERENCES IN FILE CA (1907 TO DATE) 21 REFERENCES TO NON-SPECIFIC DERIVATIVES IN FILE CA 1652 REFERENCES IN FILE CAPLUS (1907 TO DATE)

11 REFERENCES IN FILE CAOLD (PRIOR TO 1967)

=> file caplus
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SINCE FILE TOTAL
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=> d his

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FILE 'REGISTRY' ENTERED AT 14:59:37 ON 14 FEB 2008 L1 1 S 42459-51-8 L2 3 S ADAMANTOL L3 564 S ADAMANT AND OL L4564 S L3 L5 0 S ADAMANT ADJ 1 ADJ OL 564 S ADAMANT AND OL L6 L7 0 S C10H16O/MFW 5733 S C10H16O/MF 18 2 S L8 AND L6 T.9 L10 1 S 768-95-6

FILE 'CAPLUS' ENTERED AT 15:03:21 ON 14 FEB 2008

=> s 110 or 11 1652 L10 11 L1 L11 1659 L10 OR L1

=> s 11

L12 11 L1

=> d all 1-11

L12 ANSWER 1 OF 11 CAPLUS COPYRIGHT 2008 ACS on STN

AN 2007:608678 CAPLUS

DN 147:235334

ED Entered STN: 06 Jun 2007

TI An efficient method for the synthesis of enol ethers and enecarbamates. Total syntheses of isoindolobenzazepine alkaloids, lennoxamine and chilenine

AU Fuwa, Haruhiko; Sasaki, Makoto

CS Laboratory of Biostructural Chemistry, Graduate School of Life Sciences, Tohoku University, Sendai, 981-8555, Japan

SO Organic & Biomolecular Chemistry (2007), 5(12), 1849-1853 CODEN: OBCRAK; ISSN: 1477-0520

PB Royal Society of Chemistry

DT Journal

LA English

CC 31-4 (Alkaloids)

OS CASREACT 147:235334

GΙ

AB An efficient method for the synthesis of enol ethers and enecarbamates was

developed and was based on catalytic hydrosilane reduction of $\alpha\text{-phosphonoxy}$ enol ethers and $\alpha\text{-phosphonoxy}$ enecarbamates.

Ι

This method was applied to the total syntheses of two

isoindolobenzazepine

alkaloids, lennoxamine and chilenine I (R = H, X = H2; R = OH, X = O, resp.).

ST lennoxamine chilenine isoindolobenzazepine alkaloid total synthesis enol ether enecarbamate

IT Ethers, preparation

RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT (Reactant or reagent)

(enol; total syntheses of the isoindolobenzazepine alkaloids (\pm) -lennoxamine and (\pm) -chilenine via intermediate enol ethers

and enecarbamates)

IT Carbamates

```
RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (total syntheses of the isoindolobenzazepine alkaloids
        (±)-lennoxamine and (±)-chilenine via intermediate enol ethers
        and enecarbamates)
ΙT
     Alkaloids, preparation
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (total syntheses of the isoindolobenzazepine alkaloids
        (\pm)-lennoxamine and (\pm)-chilenine via intermediate enol ethers
        and enecarbamates)
ΙT
     2524-64-3
                 2861-28-1, 1,3-Benzodioxole-5-acetic acid 22483-09-6
     22635-62-7
                  26171-78-8 64482-27-5
                                           213921-40-5 945594-59-2
                  945594-69-4
     945594-63-8
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (total syntheses of the isoindolobenzazepine alkaloids
        (\pm)-lennoxamine and (\pm)-chilenine via intermediate enol ethers
        and enecarbamates)
ΤT
     33100-06-0P
                  85175-73-1P
                                 344338-21-2P
                                               385390-30-7P
                                                               945594-61-6P
                   945594-66-1P
     945594-64-9P
                                   945594-67-2P 945594-70-7P
                                                                  945594-73-0P
     945594-74-1P
                    945594-76-3P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (total syntheses of the isoindolobenzazepine alkaloids
        (±)-lennoxamine and (±)-chilenine via intermediate enol ethers
        and enecarbamates)
ΙT
     38542-77-7P, (±)-Lennoxamine 42459-51-8P
                                               71700-15-7P,
     (\pm) -Chilenine 125730-82-7P
                                   945594-60-5P
                                                  945594-62-7P
     945594-65-0P
                    945594-68-3P
                                   945594-71-8P
                                                   945594-72-9P
                                                                  945594-75-2P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (total syntheses of the isoindolobenzazepine alkaloids
        (±)-lennoxamine and (±)-chilenine via intermediate enol ethers
        and enecarbamates)
RE.CNT
       76
              THERE ARE 76 CITED REFERENCES AVAILABLE FOR THIS RECORD
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```
L12 ANSWER 2 OF 11 CAPLUS COPYRIGHT 2008 ACS on STN
AN 2006:1117842 CAPLUS
DN
   145:446291
ED Entered STN: 26 Oct 2006
TI Dry etching-resistant resists having high acid functionality, their
    additives, and their preparation
IN
    Ito, Hajime; Okada, Yasunari
   Idemitsu Kosan Co., Ltd., Japan
   Jpn. Kokai Tokkyo Koho, 16pp.
SO
    CODEN: JKXXAF
DT
   Patent
LA
    Japanese
CC
    74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
    Reprographic Processes)
    Section cross-reference(s): 38
FAN.CNT 1
    PATENT NO.
                      KIND DATE
                                        APPLICATION NO.
                                                              DATE
    _____
                             _____
                                         _____
                       ____
                       A 20061026 JP 2005-113790
20050411
                                                              20050411
    JP 2006290799
PRAI JP 2005-113790
CLASS
PATENT NO. CLASS PATENT FAMILY CLASSIFICATION CODES
[I,C*]; C07C0069-753 [I,A]; C07C0069-00 [I,C*];
                      G03F0007-004 [I,A]; C07B0061-00 [N,A]
                IPCR
                      C07C0067-00 [I,C]; C07C0067-04 [I,A]; C07B0061-00
                      [N,C]; C07B0061-00 [N,A]; C07C0067-10 [I,A];
                      C07C0069-00 [I,C]; C07C0069-753 [I,A]; G03F0007-004
                      [I,C]; G03F0007-004 [I,A]
                FTERM 2H025/AA01; 2H025/AA09; 2H025/AB16; 2H025/AC04;
                      2H025/AC08; 2H025/AD03; 2H025/BE00; 2H025/BE10;
                      2H025/BG00; 2H025/CC20; 2H025/FA41; 4H006/AA01;
                      4H006/AA02; 4H006/AA03; 4H006/AB78; 4H006/AC48;
                      4H006/BA02; 4H006/BA37; 4H006/BA66; 4H006/BJ30;
                      4H006/KC20; 4H039/CA66; 4H039/CF10; 4H039/CL25
    MARPAT 145:446291
AB
    The resists contain Z1[X(CO2Y)m]n (Z1 = alicyclic hydrocarbon; X = alicyclic hydrocarbon)
    bridging group; Y = acid-sensitive alicyclic hydrocarbyl; X and/or Y
    contain 0, N, or S; m, n \ge 1; m + n \ge 2), which are
    prepared by reacting (A) alicyclic hydrocarbon compds. having \geq 2
    carboxyls or their halides with (B) acid-sensitive alicyclic hydrocarbon
    compds. in the presence of acid or base catalysts. Further claimed are
    compds. represented by the above Markush structure where Z1 is adamantyl.
    The compds. show high solvent solubility and good compatibility with
resist
    base resins.
    dry etching resist additive polycarboxyl alicyclic compd; polycarboxyl
    adamantane added dry etching resistant resist
ΙT
    Resists
       (etching; dry etching resists containing adamantane derivs. with
plural
       carboxyl groups and showing high acid functionality)
ΙT
    913063-37-3P 913063-38-4P
```

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RL: IMF (Industrial manufacture); MOA (Modifier or additive use); TEM
     (Technical or engineered material use); PREP (Preparation); USES (Uses)
        (dry etching resists containing adamantane derivs. with plural
carboxvl
        groups and showing high acid functionality)
ΙT
     39269-10-8, 1,3-Adamantanedicarboxylic acid 42459-51-8,
     1-Adamantyl vinyl ether 625122-36-3
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (dry etching resists containing adamantane derivs. with plural
carboxyl
        groups and showing high acid functionality)
ΙT
     105-54-4, Ethyl butyrate 84540-57-8, Propylene glycol methyl ether
     acetate
     RL: TEM (Technical or engineered material use); USES (Uses)
        (resist solvents; dry etching resists containing adamantane derivs.
with
        plural carboxyl groups and showing high acid functionality)
    ANSWER 3 OF 11 CAPLUS COPYRIGHT 2008 ACS on STN
     2005:300741 CAPLUS
DN
     142:382171
ED
     Entered STN: 07 Apr 2005
     Positive resist composition and resist laminate for low-acceleration
ΤI
     electron beam and method of pattern formation
ΙN
     Ando, Tomoyuki; Hojo, Takuma
PA
     Tokyo Ohka Kogyo Co., Ltd., Japan
SO
     PCT Int. Appl., 63 pp.
     CODEN: PIXXD2
DT
    Patent
LA
     Japanese
     ICM G03F007-039
IC
     ICS G03F007-26; H01L021-027
CC
     74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
     Reprographic Processes)
FAN.CNT 1
    PATENT NO.
                         KIND DATE
                                           APPLICATION NO.
                                                                   DATE
                         ____
PΙ
     WO 2005031464
                         A1 20050407 WO 2004-JP8948
         W: AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH,
             CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD,
             GE, GH, GM, HR, HU, ID, IL, IN, IS, KE, KG, KP, KR, KZ, LC, LK,
             LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO,
             NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ,
             TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW
         RW: BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW, AM,
             AZ, BY, KG, KZ, MD, RU, TJ, TM, AT, BE, BG, CH, CY, CZ, DE, DK,
             EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE,
             SI, SK, TR, BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE,
             SN, TD, TG
     JP 2005099504
                                20050414
                                            JP 2003-334029
                                                                    20030925
                                            JP 2003-347136
     JP 2005114919
                                20050428
                                                                    20031006
                          Α
                                          JP 2003-34/136
EP 2004-746417
           6971 A1 20060607 EP 2004-746417 20040618
AT, BE, CH, DE, DK, ES, FR, GB, GR, IT, LI, LU, NL, SE, MC, PT,
     EP 1666971
             IE, SI, FI, RO, CY, TR, BG, CZ, EE, HU, PL, SK
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A1 20061026 US 2006-572709

20060317

US 2006240355

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В1
                              20070914 KR 2006-705521
                                                                 20060320
    KR 758870
PRAI JP 2003-334029
                              20030925
                       A
    JP 2003-347136
                        Α
                              20031006
    WO 2004-JP8948
                        W
                              20040618
CLASS
              CLASS PATENT FAMILY CLASSIFICATION CODES
PATENT NO.
               ____
WO 2005031464
                      G03F007-039
                ICM
                ICS
                      G03F007-26; H01L021-027
                IPCI G03F0007-039 [ICM, 7]; G03F0007-26 [ICS, 7];
H01L0021-027
                       [ICS, 7]; H01L0021-02 [ICS, 7, C*]
                IPCR
                      G03F0007-039 [I,C*]; G03F0007-039 [I,A]; G03F0007-26
                       [I,C*]; G03F0007-26 [I,A]; H01L0021-02 [I,C*];
                       H01L0021-027 [I,A]
                ECLA
                       G03F007/039C1S
JP 2005099504
                IPCR
                       G03F0007-039 [I,A]; G03F0007-039 [I,C*]; H01L0021-02
                       [I,C^*]; H01L0021-027 [I,A]
JP 2005114919
                IPCR
                       G03F0007-039 [I,A]; G03F0007-039 [I,C*]; G03F0007-11
                       [I,A]; G03F0007-11 [I,C*]; G03F0007-40 [I,A];
                       G03F0007-40 [I,C*]; H01L0021-02 [I,C*]; H01L0021-027
                       [I,A]
EP 1666971
                IPCI
                       G03F0007-039 [ICM, 7]; G03F0007-26 [ICS, 7];
H01L0021-027
                       [ICS, 7]; H01L0021-02 [ICS, 7, C*]
                IPCR
                       G03F0007-039 [I,C*]; G03F0007-039 [I,A]; G03F0007-26
                       [I,C*]; G03F0007-26 [I,A]; H01L0021-02 [I,C*];
                       H01L0021-027 [I,A]
                ECLA
                      G03F007/039C1S
                       G03C0001-00 [I,A]
US 2006240355
                IPCI
                IPCR
                       G03C0001-00 [I,C]; G03C0001-00 [I,A]; G03F0007-039
                       [I,C*]; G03F0007-039 [I,A]; G03F0007-09 [N,C*];
                       G03F0007-09 [N,A]; G03F0007-11 [N,C*]; G03F0007-11
                       [N,A]; G03F0007-20 [N,C*]; G03F0007-20 [N,A];
                       G03F0007-26 [I,C*]; G03F0007-26 [I,A]; H01L0021-02
                       [I,C*]; H01L0021-027 [I,A]
                NCL
                       430/270.100
                ECLA
                       G03F007/039C1S; S03F; S03F; S03F
KR 758870
                IPCI
                       G03F0007-039 [I,A]; H01L0021-027 [I,A]; H01L0021-02
                       [I,C*]
```

AB The invention is concerned about a pos. resist composition and resist laminate

for low-acceleration electron beams that are of high resolution and $\ensuremath{\mathsf{excel}}$ in

dry etching resistance, minimizing film loss and that accordingly can appropriately used in the process for resist pattern formation through the

step of exposure to low-acceleration electron beams. The pos. resist composition comprises a resin component (A) having acid-dissociative dissoln.

inhibiting groups so as to have an alkali solubility increased by the action of

an acid and an acid generator component (B) capable of generating an acid when exposed, wherein the remaining film ratio after alkali development in

the unexposed area of resist film formed from the pos. resist composition for $\ensuremath{\mathsf{T}}$

low-acceleration electron beams is 80% or higher. The resist laminate comprises a substrate and, sequentially superimposed thereon, a lower organic

film layer capable of dry etching, an interlayer and an upper resist film layer, wherein the upper resist film layer is formed from the above pos. resist composition for low-acceleration electron beams.

ST pos resist compn laminate electron beam pattern formation

IT Positive photoresists

(pos. resist composition and resist laminate for low-acceleration electron $% \left(1\right) =\left(1\right) +\left(1\right)$

beam pattern formation)

IT 66003-78-9, Triphenylsulfonium trifluoromethanesulfonate

RL: TEM (Technical or engineered material use); USES (Uses)

(pos. resist composition and resist laminate for low-acceleration electron $% \left(1\right) =\left(1\right) +\left(1\right)$

beam pattern formation)

IT 109-92-2DP, Ethyl vinyl ether, reaction products with hydroxystyrene copolymers 722495-59-2DP, ethoxyethyl-protected 722495-60-5DP, ethoxyethyl-protected

RL: IMF (Industrial manufacture); POF (Polymer in formulation); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses) (preparation of pos. resist composition for low-acceleration electron

pattern formation)

IT 24979-70-2D, p-Hydroxystyrene homopolymer, adamantoxyethyl-protected 24979-74-6D, p-Hydroxystyrene-styrene copolymer, adamantoxyethyl-protected

42459-51-8D, reaction products with hydroxystyrene polymers

RL: POF (Polymer in formulation); TEM (Technical or engineered material use); USES (Uses)

(preparation of pos. resist composition for low-acceleration electron beam

pattern formation)

RE.CNT 12 THERE ARE 12 CITED REFERENCES AVAILABLE FOR THIS RECORD RE

- (1) Fuji Photo Film Co Ltd; JP 2002341523 A 2002 CAPLUS
- (2) Fuji Photo Film Co Ltd; TW 562999 B 2002 CAPLUS
- (3) Fuji Photo Film Co Ltd; JP 2003177537 A 2003 CAPLUS
- (4) Matsushita Electric Industrial Co Ltd; JP 200412513 A 2004
- (5) Sony Corp; JP 2002373845 A 2002 CAPLUS
- (6) Sumitomo Chemical Co Ltd; WO 0173512 A1 2001 CAPLUS
- (7) Sumitomo Chemical Co Ltd; JP 2001272782 A 2001 CAPLUS
- (8) Sumitomo Chemical Co Ltd; US 2003113661 A1 2001 CAPLUS
- (9) Takao, U; Japanese Journal of Applied Physics, Part 1 1999, 12B, P7046
- (10) Tokyo Ohka Kogyo Co Ltd; JP 04-340553 A 1992 CAPLUS
- (11) Wako Pure Chemical Industries Ltd; JP 06-194842 A 1994 CAPLUS
- (12) Wako Pure Chemical Industries Ltd; EP 588544 A2 1994 CAPLUS
- L12 ANSWER 4 OF 11 CAPLUS COPYRIGHT 2008 ACS on STN
- AN 2004:965507 CAPLUS
- DN 141:417929
- ED Entered STN: 12 Nov 2004
- TI Positive photoresist composition and method of formation of photoresist

beam

```
patterns using the same
    Hojo, Takuma; Ishikawa, Kiyoshi
IN
PA
    Tokyo Ohka Kogyo Co., Ltd., Japan
SO
    PCT Int. Appl., 29 pp.
    CODEN: PIXXD2
DT
    Patent
LA
    Japanese
    ICM G03F007-039
IC
    ICS G03F007-004
    74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
    Reprographic Processes)
    Section cross-reference(s): 35
FAN.CNT 1
    PATENT NO.
                      KIND DATE
                                        APPLICATION NO.
                                                              DATE
                      ----
                                         _____
    WO 2004097524 A1 20041111 WO 2004-JP5402
                                                              20040415
PΙ
        W: AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH,
            CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD,
            GE, GH, GM, HR, HU, ID, IL, IN, IS, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO,
            NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ,
        SK, TR, BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN,
            TD, TG
                                       JP 2003-125242
    JP 2004333549
                        Α
                              20041125
                                                               20030430
                        A1 20060125 EP 2004-727762
                                                              20040415
    EP 1619553
        R: AT, BE, CH, DE, DK, ES, FR, GB, GR, IT, LI, LU, NL, SE, MC, PT,
            IE, SI, LT, LV, FI, RO, MK, CY, AL, TR, BG, CZ, EE, HU, PL, SK,
HR
                                         TW 2004-93111275
    TW 276920
                       В
                              20070321
                                                               20040422
                       A1 20061102
    US 2006247346
                                         US 2005-553083
                                                               20051011
                       A
PRAI JP 2003-125242
                             20030430
    WO 2004-JP5402
                              20040415
CLASS
PATENT NO. CLASS PATENT FAMILY CLASSIFICATION CODES
WO 2004097524 ICM G03F007-039
                ICS
                     G03F007-004
                      G03F0007-039 [ICM, 7]; G03F0007-004 [ICS, 7]
                IPCI
                IPCR
                      C08F0008-00 [I,C*]; C08F0008-00 [I,A]; G03F0007-039
                      [I,C*]; G03F0007-039 [I,A]; H01L0021-02 [I,C*];
                      H01L0021-027 [I,A]
                ECLA
                      G03F007/039C1S
                      G03F0007-039 [I,A]; G03F0007-039 [I,C*]
JP 2004333549
                IPCR
EP 1619553
                IPCI
                      G03F0007-039 [ICM, 7]; G03F0007-004 [ICS, 7]
                IPCR
                      C08F0008-00 [I,C*]; C08F0008-00 [I,A]; G03F0007-039
                      [I,C*]; G03F0007-039 [I,A]; H01L0021-02 [I,C*];
                      H01L0021-027 [I,A]
                ECLA
                      G03F007/039C1S
TW 276920
                      G03F0007-039 [I,C]; G03F0007-039 [I,A]
                IPCI
                IPCR
                      C08F0008-00 [I,C*]; C08F0008-00 [I,A]; H01L0021-02
                      [I,C*]; H01L0021-027 [I,A]
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G03F007/039C1S
                 ECLA
                        C08K0005-41 [I,A]; C08K0005-00 [I,C*]
US 2006247346
                 IPCI
                 IPCR
                        C08K0005-00 [I,C]; C08K0005-41 [I,A]; C08F0008-00
                        [I,C*]; C08F0008-00 [I,A]; G03F0007-039 [I,C*];
                        G03F0007-039 [I,A]; H01L0021-02 [I,C*]; H01L0021-027
                        [I,A]
                 NCL
                        524/155.000; 524/577.000
                        G03F007/039C1S
                 ECLA
     The invention provides a pos. photoresist composition which has high
etching
     resistance and attains high resolution and a method of forming patterns
     using the resist composition The pos. resist composition contains a
resin component
     (A) which has acid-dissociable dissoln.-inhibiting groups and can be
     enhanced in the solubility in alkali by the action of an acid and an acid
     generator component (B) which generates an acid upon exposure, the resin
     component (A) being a polymer comprising structural units of
     hydroxyphenylethylenyl group and part of the hydroxyl groups of the units
     being protected by replacing the hydrogen atoms by acid-dissociable
     dissoln.-inhibiting groups represented by the general formula
     -C(R1)(R2)C-O-X wherein R1 is alkyl having 1 to 5 carbon atoms; R2 is
     alkyl having 1 to 5 carbon atoms or hydrogen; and X is an aliphatic
     polycyclic group having 10 to 16 carbon atoms or an aromatic polycyclic
     hydrocarbon group having 10 to 16 carbon atoms.
ST
    pos photoresist compn polymer
ΙT
    Positive photoresists
        (pos. photoresist composition and method of formation of photoresist
        patterns using the same)
TΤ
     66003-78-9, Triphenylsulfonium trifluoromethanesulfonate
                                                                193222-02-5,
     \alpha-(Methylsulfonyloxyimino)-4-methoxyphenylacetonitrile
     RL: TEM (Technical or engineered material use); USES (Uses)
        (acid generator; pos. photoresist composition)
ΤТ
     24979-70-2D, p-Hydroxystyrene homopolymer, reaction product with
     1-Adamantyl vinyl ether
                               27364-41-6D, reaction product with
     hydroxystyrenyl polymer 42459-51-8D, 1-Adamantyl vinyl ether,
     reaction product with hydroxystyrenyl polymer
     RL: TEM (Technical or engineered material use); USES (Uses)
        (pos. photoresist composition)
RE.CNT
       10
              THERE ARE 10 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE
(1) Fuji Photo Film Co Ltd; JP 2002139838 A 2002 CAPLUS
(2) Fuji Photo Film Co Ltd; JP 2002323768 A 2002 CAPLUS
(3) Fuji Photo Film Co Ltd; JP 2003307840 A 2003 CAPLUS
(4) Jsr Corp; JP 11-2902 A 1999 CAPLUS
(5) Jsr Corp; JP 11-30865 A 1999 CAPLUS
(6) Jsr Corp; JP 2001316418 A 2001 CAPLUS
(7) Shin-Etsu Chemical Co Ltd; JP 2002234910 A 2002 CAPLUS
(8) Shipley Co L L C; US 2003232273 A1 2003 CAPLUS
(9) Shipley Co L L C; JP 2003295444 A 2003 CAPLUS
(10) Wako Pure Chemical Industries Ltd; JP 08-123032 A 1996 CAPLUS
    ANSWER 5 OF 11 CAPLUS COPYRIGHT 2008 ACS on STN
ΑN
     2003:585195 CAPLUS
DN
     139:133273
```

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Entered STN: 30 Jul 2003
ED
TI Preparation of (meth)acryloyl-containing adamantane derivatives
IN Anzai, Ryuichi; Kikuchi, Katsuaki
PA
   Mitsubishi Rayon Co., Ltd., Japan
SO Jpn. Kokai Tokkyo Koho, 8 pp.
    CODEN: JKXXAF
DT
   Patent
   Japanese
LA
    ICM C07C067-04
IC
    ICS C07C067-29; C07C069-54; C07C213-08; C07C217-52; C07B061-00
CC
    24-8 (Alicyclic Compounds)
    Section cross-reference(s): 35
FAN.CNT 1
                     KIND DATE
                                       APPLICATION NO.
    PATENT NO.
                                                             DATE
                      ____
                                         _____
                      A 20030755
B2 20080109
A 20071206
    JP 2003212823
                            20030730 JP 2002-10155
                                                             20020118
PΤ
    JP 4030313
                                                              20070806
    JP 2007314570
                                        JP 2007-203922
                       А3
                             20020118
PRAI JP 2002-10155
CLASS
PATENT NO. CLASS PATENT FAMILY CLASSIFICATION CODES
 _____
JP 2003212823 ICM
                     C07C067-04
               ICS
                      C07C067-29; C07C069-54; C07C213-08; C07C217-52;
                      C07B061-00
                IPCI
                      C07C0067-04 [I,A]; C07C0067-29 [I,A]; C07C0067-00
                      [I,C*]; C07C0069-54 [I,A]; C07C0069-00 [I,C*];
                      C07C0213-08 [I,A]; C07C0213-00 [I,C*]; C07C0217-52
                      [I,A]; C07C0217-00 [I,C*]; C07B0061-00 [N,A]
                      C07C0067-04 [I,A]; C07B0061-00 [I,C*]; C07B0061-00
                TPCR
                      [I,A]; C07C0067-00 [I,C*]; C07C0067-29 [I,A];
                      C07C0069-00 [I,C*]; C07C0069-54 [I,A]; C07C0213-00
                      [I,C*]; C07C0213-08 [I,A]; C07C0217-00 [I,C*];
                      C07C0217-52 [I,A]
[I,A]; C07C0069-00 [I,C*]; C07C0217-52 [I,A];
                      C07C0217-00 [I,C*]; C07C0213-08 [I,A]; C07C0213-00
                      [I,C*]; C07B0061-00 [N,A]
                FTERM 4H006/AA02; 4H006/AC48; 4H006/BA11; 4H006/BA13;
                      4H006/BA37; 4H006/BA52; 4H006/BA66; 4H006/BJ30;
                      4H006/KA11; 4H039/CA66; 4H039/CF10
    MARPAT 139:133273
OS
   CH:CR1CO2CHMeO(CH2)nR2 [I; R1 = H, Me; R2 = (un)substituted adamantyl,
AB
    adamantanonyl (sic); n = 0-4], useful as materials for drugs, agrochems.,
    polymers, etc., are prepared by treating CH:CR1CO2CH:CH2 (R1 = same as
    above) with R2(CH2)nOH (R2 = same as above), preferably in the presence
of
    acid catalysts. Alternatively I are prepared by treating CH:CR1CO2H with R2(CH2)nOH:CH2. A mixture of 1-adamantanol, vinyl acrylate, and
    Bi(OSO2CF3)3.4H2O was heated at 40^{\circ} for 8 h to give 53% I (R1 = H,
    R2 = 1-adamantyl, n = 0).
    adamantyloxyethyl acrylate prepn; adamantanol addn vinyl acrylate bismuth
ST
    triflate catalyst; acid catalyst adamantyl vinyl ether addn methacrylic
    acid
ΙT
    Acids, uses
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```
Lewis acids
     RL: CAT (Catalyst use); USES (Uses)
        (preparation of (meth)acryloyl-containing adamantane derivs. from
vinvl
        (meth)acrylate and adamantyl alcs. or from (meth)acrylic acid and
        adamantyl alcs.)
ΙT
     104-15-4, p-Toluenesulfonic acid, uses 109-63-7, Boron trifluoride
     diethyl ether complex 4124-42-9, Ammonium p-toluenesulfonate
     7646-78-8, Tin(IV) chloride, uses
                                         7646-85-7, Zinc chloride, uses
     7787-60-2, Bismuth chloride
                                   88189-03-1
     RL: CAT (Catalyst use); USES (Uses)
        (preparation of (meth)acryloyl-containing adamantane derivs. from
vinyl
        (meth)acrylate and adamantyl alcs. or from (meth)acrylic acid and
        adamantyl alcs.)
     279218-82-5P
                   569329-57-3P
                                    569329-58-4P
                                                   569329-59-5P
                                                                   569329-60-8P
ΤТ
     569329-61-9P
                    569329-62-0P
                                    569329-64-2P
                                                   569329-66-4P
     RL: IMF (Industrial manufacture); SPN (Synthetic preparation); PREP
     (Preparation)
        (preparation of (meth)acryloyl-containing adamantane derivs. from
vinyl
        (meth)acrylate and adamantyl alcs. or from (meth)acrylic acid and
        adamantyl alcs.)
     79-10-7, Acrylic acid, reactions 79-41-4, Methacrylic acid, reactions 700-57-2, 2-Adamantanol 702-98-7, 2-Methyl-2-adamantanol 768-95-6,
TΤ
                     770-71-8, 1-Adamantanemethanol
     1-Adamantanol
                                                       2177-18-6, Vinvl
acrylate
     4245-37-8, Vinyl methacrylate 5001-18-3, 1,3-Dihydroxyadamantane
     42459-51-8, 1-Adamantyl vinyl ether 124261-95-6, 2-Adamantyl
                                                                  569329-63-1,
                   262617-15-2, 1-Adamantylmethyl vinyl ether
     vinyl ether
     3-Methyl-1-adamantyl vinyl ether 569329-65-3, 1-Amino-2-adamantyl vinyl
     ether
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (preparation of (meth)acryloyl-containing adamantane derivs. from
vinyl
        (meth)acrylate and adamantyl alcs. or from (meth)acrylic acid and
        adamantyl alcs.)
L12 ANSWER 6 OF 11 CAPLUS COPYRIGHT 2008 ACS on STN
     2003:391375 CAPLUS
DN
     139:149191
    Entered STN: 22 May 2003
ED
     Synthesis of Allyl and Alkyl Vinyl Ethers Using an in Situ Prepared
ΤI
     Air-Stable Palladium Catalyst. Efficient Transfer Vinylation of Primary,
     Secondary, and Tertiary Alcohols
     Bosch, Martin; Schlaf, Marcel
ΑU
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Department of Chemistry and Biochemistry, Guelph-Waterloo Centre for

Journal of Organic Chemistry (2003), 68(13), 5225-5227

Graduate Work in Chemistry (GWC)2, University of Guelph, Guelph, ON, N1G

DT Journal LA English

2W1, Can.

CC 21-2 (General Organic Chemistry)

American Chemical Society

CODEN: JOCEAH; ISSN: 0022-3263

CS

SO

PΒ

CASREACT 139:149191

OS

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AB
    An air-stable palladium catalyst formed in situ from com. available
     components efficiently catalyzed the transfer vinylation between Bu vinyl
     ether and various allyl and alkyl alcs. to give the corresponding allyl
     and alkyl vinyl ethers in 61-98% yield in a single step.
ST
     ether allyl alkyl vinyl prepn alc vinylation palladium catalyst
    Etherification
    Etherification catalysts
    Vinvlation
    Vinylation catalysts
        (synthesis of allyl and alkyl vinyl ethers via transfer vinylation of
        primary, secondary, and tertiary alcs. using an in situ prepared
        air-stable palladium catalyst)
     Alcohols, reactions
ΙT
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (synthesis of allyl and alkyl vinyl ethers via transfer vinylation of
        primary, secondary, and tertiary alcs. using an in situ prepared
        air-stable palladium catalyst)
ΙT
     Ethers, preparation
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (vinyl; synthesis of allyl and alkyl vinyl ethers via transfer
        vinylation of primary, secondary, and tertiary alcs. using an in situ
        prepared air-stable palladium catalyst)
     1662-01-7, 4,7-Diphenyl-1,10-phenanthroline
                                                  3375-31-3 42196-31-6,
     Palladium trifluoroacetate
     RL: CAT (Catalyst use); USES (Uses)
        (synthesis of allyl and alkyl vinyl ethers via transfer vinylation of
       primary, secondary, and tertiary alcs. using an in situ prepared
        air-stable palladium catalyst)
     75-65-0, tert.-Butyl alcohol, reactions 78-70-6, Linalool
ΤT
     Menthol 96-41-3, Cyclopentanol 98-85-1, 1-Phenylethanol
                                                                   100-51-6,
     Benzyl alcohol, reactions 107-18-6, Allyl alcohol, reactions
108-93-0,
    Cyclohexanol, reactions 556-82-1, 3-Methyl-2-buten-1-ol
     1,6-Hexanediol
                     768-95-6, 1-Adamantanol 821-09-0, 4-Penten-1-ol
     822-67-3, 2-Cyclohexen-1-ol 3623-51-6, Neomenthol 3623-52-7,
     Isomenthol 18457-55-1, (S)-(-)-Perillyl alcohol
                                                       39161-19-8,
                    308363-12-4, (R)-(-)-Carveol
     3-Penten-1-ol
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (synthesis of allyl and alkyl vinyl ethers via transfer vinylation of
       primary, secondary, and tertiary alcs. using an in situ prepared
        air-stable palladium catalyst)
                                   764-47-6, Propyl vinyl ether
ΤТ
     111-34-2, Butyl vinyl ether
     RL: RGT (Reagent); RACT (Reactant or reagent)
        (synthesis of allyl and alkyl vinyl ethers via transfer vinylation of
       primary, secondary, and tertiary alcs. using an in situ prepared
        air-stable palladium catalyst)
ΙT
     926-02-3P, tert.-Butyl vinyl ether
     RL: RGT (Reagent); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (synthesis of allyl and alkyl vinyl ethers via transfer vinylation of
        primary, secondary, and tertiary alcs. using an in situ prepared
        air-stable palladium catalyst)
ΙT
     928-41-6P 935-04-6P, Benzyl vinyl ether 2100-16-5P, 1-Phenylethyl
     vinyl ether 2182-55-0P, Cyclohexyl vinyl ether 3917-15-5P, Allyl
vinyl
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ether 5989-48-0P 19763-13-4P 42459-51-8P, 1-Adamantyl vinyl ether 80816-25-7P 176207-95-7P 193977-16-1P 193977-18-3P
     344329-17-5P 570432-56-3P 570432-57-4P 570432-58-5P 570432-59-6P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (synthesis of allyl and alkyl vinyl ethers via transfer vinylation of
        primary, secondary, and tertiary alcs. using an in situ prepared
        air-stable palladium catalyst)
RE.CNT 3
             THERE ARE 3 CITED REFERENCES AVAILABLE FOR THIS RECORD
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L12 ANSWER 7 OF 11 CAPLUS COPYRIGHT 2008 ACS on STN
    2003:172957 CAPLUS
ΑN
   138:206865
DN
   Entered STN: 07 Mar 2003
ED
TI Preparation of vinyl ether compounds using transition metal compound
     catalysts
     Ishii, Yasutaka; Nakano, Tatsuya; Inoue, Keizo
ΙN
    Daicel Chemical Industries, Ltd., Japan
    Eur. Pat. Appl., 24 pp.
    CODEN: EPXXDW
DT
    Patent
LA
    English
IC
     ICM C07C049-453
     ICS C07C041-16; C07C069-74; C07D315-00; C07D313-02; C07C069-00;
          C07C043-16
CC
     45-4 (Industrial Organic Chemicals, Leather, Fats, and Waxes)
     Section cross-reference(s): 67
FAN.CNT 1
     ____ KIND DATE
_____EP 1288196
     PATENT NO.
                                            APPLICATION NO.
                                                                    DATE
                        ____
                                             ______
                        A2 20030305 EP 2002-19088
    EP 1288186
PΙ
                                                                    20020828
                     A3 20030917
B1 20070919
     EP 1288186
     EP 1288186
         R: AT, BE, CH, DE, DK, ES, FR, GB, GR, IT, LI, LU, NL, SE, MC, PT,
             IE, SI, LT, LV, FI, RO, MK, CY, AL, TR, BG, CZ, EE, SK

      JP 2003073321
      A
      20030312
      JP 2001-261632
      20010830

      EP 1826196
      A2
      20070829
      EP 2007-11396
      20020828

                          A3 20071114
     EP 1826196
        R: DE, FR, GB
     US 2003083529 A1 20030501 US 2002-231115
US 7074970 B2 20060711
                                                                    20020830
    US 2006205957 A1
US 7271297 B2
                                20060914 US 2006-437616 20060522
                                20070918
PRAI JP 2001-261632 A 20010830
EP 2002-19088 A3 20020828
US 2002-231115 A3 20020830
 PATENT NO. CLASS PATENT FAMILY CLASSIFICATION CODES
 EP 1288186 ICM C07C049-453
                 ICS
                        C07C041-16; C07C069-74; C07D315-00; C07D313-02;
```

C07C069-00; C07C043-16

```
IPCI
                       C07C0041-00 [I,C]; C07C0041-16 [I,A]; C07C0043-00
                        [I,C]; C07C0043-162 [I,A]; C07C0049-00 [I,C];
                        C07C0049-753 [I,A]; C07C0069-00 [I,C]; C07C0069-00
                        [I,A]; C07D0307-00 [I,C]; C07D0307-32 [I,A];
                        C07D0307-93 [I,A]; C07D0313-00 [I,C]; C07D0313-10
[I,A]
                 IPCR
                        C07B0061-00 [I,C*]; C07B0061-00 [I,A]; C07C0043-16
                        [I,A]; C07C0043-166 [I,A]; C07C0043-188 [I,A];
                        C07C0043-215 [I,A]; C07C0067-00 [I,C*]; C07C0067-31
                        [I,A]; C07C0069-757 [I,A]; C07D0307-33 [I,A];
                        C07D0493-00 [I,C*]; C07D0493-04 [I,A]
                 ECLA
                        C07C041/16; C07C043/162; C07C049/753;
                        C07C067/31+69/00J1; C07C069/00J1; C07D307/32C;
                        C07D307/93; C07D313/10; C07C069/757; M07C
                        C07B0061-00 [I,C*]; C07B0061-00 [I,A]; C07C0041-00
JP 2003073321
                IPCR
                        [I,C*]; C07C0041-16 [I,A]; C07C0043-00 [I,C*];
                        C07C0043-16 [I,A]; C07C0043-162 [I,A]; C07C0043-166
                        [I,A]; C07C0043-188 [I,A]; C07C0043-215 [I,A];
                        C07C0049-00 [I,C*]; C07C0049-753 [I,A]; C07C0067-00
                        [I,C*]; C07C0067-31 [I,A]; C07C0069-00 [I,C*];
                        C07C0069-00 [I,A]; C07C0069-757 [I,A]; C07D0307-00
                        [I,C*]; C07D0307-33 [I,A]; C07D0307-93 [I,A];
                        C07D0313-00 [I,C*]; C07D0313-10 [I,A]; C07D0493-00
                        [I,C*]; C07D0493-04 [I,A]
EP 1826196
                 IPCI
                        C07C0069-00 [I,A]; C07C0049-753 [I,A]; C07C0049-00
                        [I,C*]; C07C0043-162 [I,A]; C07C0043-00 [I,C*];
                        C07D0307-32 [I,A]; C07D0307-93 [I,A]; C07D0307-00
                        [I,C*]; C07D0313-10 [I,A]; C07D0313-00 [I,C*];
                        C07C0069-757 [I,A]
                        C07C043/162; C07C049/753; C07C069/00J1; C07C069/757;
                 ECLA
                        C07D307/32C; C07D307/93; C07D313/10; M07C
US 2003083529
                 IPCI
                        C07C0043-00 [I,A]
                       C07B0061-00 [I,C*]; C07B0061-00 [I,A]; C07C0041-00
                 IPCR
                        [I,C*]; C07C0041-16 [I,A]; C07C0043-00 [I,C*];
                        C07C0043-16 [I,A]; C07C0043-162 [I,A]; C07C0043-166
                        [I,A]; C07C0043-188 [I,A]; C07C0043-215 [I,A];
                        C07C0049-00 [I,C*]; C07C0049-753 [I,A]; C07C0067-00
                        [I,C*]; C07C0067-31 [I,A]; C07C0069-00 [I,C*];
                        C07C0069-00 [I,A]; C07C0069-757 [I,A]; C07D0307-00
                        [I,C*]; C07D0307-33 [I,A]; C07D0307-93 [I,A];
                        C07D0313-00 [I,C*]; C07D0313-10 [I,A]; C07D0493-00
                        [I,C*]; C07D0493-04 [I,A]
                 NCL
                        568/671.000
                 ECLA
                        C07C041/16; C07C043/162; C07C049/753;
                        C07C067/31+69/00J1; C07C069/00J1; C07D307/32C;
                        C07D307/93; C07D313/10
                        C07D0307-77 [I,A]; C07D0307-92 [I,A]; C07D0307-00
US 2006205957
                 IPCI
                        [I,C*]; C07C0043-18 [I,A]; C07C0043-16 [I,A];
                        C07C0043-00 [I,C*]; C07C0051-00 [I,A]
                 IPCR
                        C07D0307-00 [I,C]; C07D0307-77 [I,A]; C07B0061-00
                        [I,C*]; C07B0061-00 [I,A]; C07C0041-00 [I,C*];
                        C07C0041-16 [I,A]; C07C0043-00 [I,C]; C07C0043-16
                        [I,A]; C07C0043-162 [I,A]; C07C0043-166 [I,A];
                        C07C0043-18 [I,A]; C07C0043-188 [I,A]; C07C0043-215
                        [I,A]; C07C0049-00 [I,C*]; C07C0049-753 [I,A];
```

```
[I,C*]; C07C0069-00 [I,A]; C07C0069-757 [I,A];
                        C07D0307-33 [I,A]; C07D0307-92 [I,A]; C07D0307-93
                        [I,A]; C07D0313-00 [I,C*]; C07D0313-10 [I,A];
                        C07D0493-00 [I,C*]; C07D0493-04 [I,A]
                 NCL
                        549/240.000; 568/665.000; 549/299.000; 549/306.000;
                        562/887.000
                 ECLA
                        C07C041/16; C07C043/162; C07C049/753;
                        C07C067/31+69/00J1; C07C069/00J1; C07D307/32C;
                        C07D307/93; C07D313/10; C07C069/757; M07C
OS
    MARPAT 138:206865
    The title process produces vinyl ether compds. and includes allowing a
AB
    vinyl ester compound R1CO2CR2:CR3R4 wherein R1, R2, R3 and R4 are the
same
     or different and are each a hydrogen atom or an organic group, to react
with
     a hydroxy compound R50H wherein R5 is an organic group, in the presence
of at
     least one transition element compound to thereby yield a vinyl ether
compound
     R5OCR2:CR3R4 wherein R2, R3, R4 and R5 have the same meanings as defined
     above. Such transition element compds. include iridium compds. and other
     compds. containing Group VIII elements.
ST
     vinyl ether prepn transition metal compd catalyst
ΙT
     Transition metal compounds
    RL: CAT (Catalyst use); USES (Uses)
        (preparation of vinyl ether compds. using transition metal compound
catalysts)
     Ethers, preparation
IΤ
     RL: IMF (Industrial manufacture); PREP (Preparation)
        (vinyl; preparation of vinyl ether compds. using transition metal
compound
        catalysts)
ΤТ
     12080-32-9, Dichloro(1,5-cyclooctadiene)platinum
                                                        12092-47-6,
     Di-\mu-chlorobis (1,5-cyclooctadiene) dirhodium
                                                 12112-67-3
                                                                32679-03-1,
     (1,5-Cyclooctadiene) bis (acetonitrile) iridium tetrafluoroborate
                  50982-12-2, Dichloro(1,5-cyclooctadiene)ruthenium
     35138-23-9
     RL: CAT (Catalyst use); USES (Uses)
        (preparation of vinyl ether compds. using transition metal compound
catalysts)
ΤТ
     765-12-8P, Triethylene glycol divinyl ether
                                                 766-94-9P, Phenyl vinyl
            929-62-4P
                        929-72-6P, Triethylene glycol monovinyl ether
     930-30-3P, 2-Cyclopenten-1-one
                                    935-04-6P, Benzyl vinyl ether
     2100-16-5P 6192-15-0P
                             19763-13-4P, 1,6-Bis(vinyloxy)hexane
     27336-16-9P 42459-51-8P, 1-Adamantyl vinyl ether
                                                       46173-76-6P
                   88739-04-2P 406226-15-1P
                                                424826-89-1P
     52169-16-1P
                                                              500541-84-4P
                                   500541-87-7P
                                                  500541-88-8P
     500541-85-5P
                    500541-86-6P
                                                                 500541-89-9P
     500541-90-2P
                    500541-91-3P
                                   500541-92-4P
                                                  500541-93-5P
                                                                 500541-94-6P
     500541-95-7P
                    500541-98-0P
                                   500541-99-1P
     RL: IMF (Industrial manufacture); PREP (Preparation)
        (preparation of vinyl ether compds. using transition metal compound
catalysts)
     98-85-1, sec-Phenethyl alcohol 100-51-6, Benzyl alcohol, reactions
     108-05-4, Vinyl acetate, reactions 108-22-5, Isopropenyl acetate
     108-95-2, Phenol, reactions 111-87-5, 1-Octanol, reactions
                                                                    112-27-6,
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C07C0067-00 [I,C*]; C07C0067-31 [I,A]; C07C0069-00

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Triethylene glycol 629-11-8, 1,6-Hexanediol 768-95-6, 1-Adamantanol
     775-64-4 933-48-2 1490-04-6, Menthol 3212-60-0, 2-Cyclopenten-1-ol
     5001-18-3, 1,3-Adamantanediol 13416-69-8, \alpha-Hydroxy-
    \gamma, \gamma-dimethyl-\gamma-butyrolactone
                                    20098-14-0,
                                        96314-52-2, 1-Hydroxy-4-
     4-0xo-1-adamantanol
                           92343-46-9
     oxatricyclo[4.3.1.13,8]undecan-5-one 99181-50-7, 1,3,5-Adamantanetriol
     421555-75-1
                  437754-44-4
                                 500541-96-8 500541-97-9
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (preparation of vinyl ether compds. using transition metal compound
catalysts)
L12 ANSWER 8 OF 11 CAPLUS COPYRIGHT 2008 ACS on STN
    2002:96169 CAPLUS
ΑN
    136:279091
DN
    Entered STN: 06 Feb 2002
ED
     Development of a Highly Efficient Catalytic Method for Synthesis of Vinyl
TΤ
     Ethers
ΑU
    Okimoto, Yoshio; Sakaguchi, Satoshi; Ishii, Yasutaka
CS
     Department of Applied Chemistry, Faculty of Engineering, Kansai
     University, Suita, Osaka, 564-8680, Japan
    Journal of the American Chemical Society (2002), 124(8), 1590-1591
SO
    CODEN: JACSAT; ISSN: 0002-7863
    American Chemical Society
PB
    Journal
DT
LA
    English
CC
     23-9 (Aliphatic Compounds)
OS
    CASREACT 136:279091
AΒ
    A new method for the preparation of alkyl vinyl ethers has been
developed.
     Thus, vinyl ethers ROCH: CH2 (R = Octyl, PhCH2, PhCHMe, Menthyl,
     Adamant-1-yl, Ph) were synthesized by the reaction of alcs. with vinyl
     acetate under the influence of a catalytic amount of [Ir(cod)Cl]2
combined
    with Na2CO3 in good to excellent yields. Similarly, divinyl ethers, e.g.
    CH2:CHOCH2(CH2)4CH2OCH:CH2 were also prepared from the corresponding
ST
    vinyl ether prepn; vinylation alc vinyl acetate iridium catalyst
ΙT
    Vinvlation
     Vinylation catalysts
        (preparation of vinyl ethers via Ir-catalyzed vinylation of alcs.
with vinvl
        acetate in the presence of inorg. sodium salts as additives)
     Alcohols, reactions
ΤТ
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (preparation of vinyl ethers via Ir-catalyzed vinylation of alcs.
with vinvl
        acetate in the presence of inorg. sodium salts as additives)
ΙT
     Ethers, preparation
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (vinyl; preparation of vinyl ethers via Ir-catalyzed vinylation of
alcs.
       with vinyl acetate in the presence of inorg. sodium salts as
additives)
     12112-67-3, Dichlorobiscyclooctadienediiridium 32679-03-1,
     Bisacetonitrile(1,5-cyclooctadiene)iridium(1+) tetrafluoroborate
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35138-23-9, Bis(1,5-cyclooctadiene)iridium(1+) tetrafluoroborate
     RL: CAT (Catalyst use); USES (Uses)
        (preparation of vinyl ethers via Ir-catalyzed vinylation of alcs.
with vinyl
       acetate in the presence of inorg. sodium salts as additives)
     80-05-7, Bisphenol-A, reactions 98-85-1, 1-Phenylethanol 100-51-6,
     Benzyl alcohol, reactions
                                 108-05-4, Vinyl acetate, reactions
108-95-2,
                        108-98-5, Thiophenol, reactions
     Phenol, reactions
1-Octanol,
     reactions
               112-27-6, Bis-1,2-(2-hydroxyethoxy)ethane
                                                               123-31-9,
     1,4-Dihydroxybenzene, reactions 629-11-8, 1,6-Hexanediol 768-95-6,
     Adamantan-1-ol 769-78-8, Vinyl benzoate
                                                 1490-04-6, Menthol
     5001-18-3, 1,3-Adamantanediol
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (preparation of vinyl ethers via Ir-catalyzed vinylation of alcs.
with vinyl
        acetate in the presence of inorg. sodium salts as additives) 7-09-3, Sodium acetate 144-55-8, Sodium bicarbonate, reactions
     127-09-3, Sodium acetate
     497-19-8, Sodium carbonate, reactions
     RL: RGT (Reagent); RACT (Reactant or reagent)
        (preparation of vinyl ethers via Ir-catalyzed vinylation of alcs.
with vinyl
        acetate in the presence of inorg. sodium salts as additives)
ΙT
     108-22-5P, Isopropenyl acetate 765-12-8P, Triethylene glycol divinyl
     ether 766-94-9P, Phenyl vinyl ether 935-04-6P, Benzyl vinyl ether
     1822-73-7P, Phenyl vinyl thioether 2100-16-5P, 1-Phenylethyl vinyl
ether
     3754-60-7P, Bisphenol-A divinyl ether
                                              4024-21-9P, 1,4-
     Bis(vinyloxy)benzene 19763-13-4P, 1,6-Bis(vinyloxy)hexane
     42459-51-8P, 1-Adamantyl vinyl ether 46173-76-6P 52169-16-1P
     406226-15-1P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (preparation of vinyl ethers via Ir-catalyzed vinylation of alcs.
with vinyl
        acetate in the presence of inorq. sodium salts as additives)
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- AN 1995:176654 CAPLUS
- DN 122:55856
- ED Entered STN: 09 Nov 1994
- TI Improved enantioselectivity in the inverse electron demand Diels-Alder cycloadditions of 3-carbomethoxy-2-pyrone catalyzed by chiral ytterbium complexes
- AU Marko, Istvan F.; Evans, Graham R.
- CS Lab. Chim. Org., Univ. Catholique Louvain, Louvain-la-Neuve, B-1348, Belg.
- SO Bulletin des Societes Chimiques Belges (1994), 103(5-6), 295-7 CODEN: BSCBAG; ISSN: 0037-9646
- DT Journal
- LA English
- CC 27-13 (Heterocyclic Compounds (One Hetero Atom))
- OS CASREACT 122:55856
- AB Yb(OTf)3 (Tf = CF3SO2) in combination with (R)-(+)-Binol catalyzed the enantion selective inverse electron demand Diels Alder cycloaddn.
- reactions of 3-carbomethoxy-2-pyrone with vinyl ethers and vinyl sulfides.
- ST stereochem Diels Alder carbomethoxypyrone catalyst; ytterbium triflate catalyst enantioselective Diels Alder; oxabicyclooctenone carbomethoxy alkoxy alkylthio
- IT Diels-Alder reaction catalysts

Stereochemistry

(chiral ytterbium catalyst for enantioselective inverse electron demand

Diels-Alder cycloaddns. of 3-carbomethoxy-2-pyrone)

IT 18531-94-7, (R)-BINOL 54761-04-5, Ytterbium triflate RL: CAT (Catalyst use); USES (Uses)

(chiral ytterbium catalyst for enantioselective inverse electron demand

Diels-Alder cycloaddns. of 3-carbomethoxy-2-pyrone) 111-34-2, Butyl vinyl ether 1822-73-7, Phenyl vinyl sulfide ΙT 2182-55-0, Cyclohexyl vinyl ether 4789-70-2, Butyl vinyl sulfide 25991-27-9 42459-51-8, 1-Adamantyl vinyl ether RL: RCT (Reactant); RACT (Reactant or reagent) (chiral ytterbium catalyst for enantioselective inverse electron demand Diels-Alder cycloaddns. of 3-carbomethoxy-2-pyrone) ΙT 156899-10-4P 156899-11-5P 157007-16-4P 159951-54-9P 159951-55-0P RL: SPN (Synthetic preparation); PREP (Preparation) (chiral ytterbium catalyst for enantioselective inverse electron demand Diels-Alder cycloaddns. of 3-carbomethoxy-2-pyrone) ANSWER 10 OF 11 CAPLUS COPYRIGHT 2008 ACS on STN 1994:508443 CAPLUS ΑN 121:108443 DN EDEntered STN: 03 Sep 1994 Catalytic, enantioselective, inverse electron-demand Diels-Alder (IEDDA) ΤI reactions of 3-carbomethoxy-2-pyrone (3-CMP) Marko, Istvan E.; Evans, Graham R. ΑU Univ. Catholique Louvain, Dep. Chim., Louvain-La-Neuve, B-1348, Belg. CS Tetrahedron Letters (1994), 35(17), 2771-4 CODEN: TELEAY; ISSN: 0040-4039 DTJournal English LA CC 27-13 (Heterocyclic Compounds (One Hetero Atom)) Section cross-reference(s): 24 OS CASREACT 121:108443 GΙ

AB Cycloaddn. reactions between title pyrone and vinyl ethers and sulfides, catalyzed by the Yb(OTf)3-Binol complex, gave 70-97% bicyclic lactones I (R = e.g., EtO, EtS, PhCH2O, cymyloxy, adamantyloxy, PhS) in moderate to excellent enantiomeric excesses. Enantioselectivity increased with increasing substituent size in the vinyl ethers or sulfides.

ST inverse electron demand Diels Alder pyrone; bicyclic lactone prepn enantioselectivity; substituent effect enantioselectivity bicyclic

prepn; vinyl ether Diels Alder pyrone enantioselectivity; sulfide vinyl Diels Alder pyrone enantioselectivity

IT Diels-Alder reaction catalysts

(inverse electron-demand, europium complexes with binol, for pyrone with vinyl ethers or sulfides, enantioselectivity of)

```
ΙT
     Substituent effect
        (on enantioselectivity of catalytic inverse electron-demand
Diels-Alder
        cycloaddn. of pyrone with vinyl ethers or sulfides)
ΙT
     Diels-Alder reaction
        (inverse-electron-demand, of pyrone with vinyl ethers or sulfides,
        enantioselectivity of)
ΙT
     18531-99-2
     RL: CAT (Catalyst use); USES (Uses)
        (catalyst containing, for inverse electron-demand Diels-Alder
cycloaddn. of
        vinyl ethers or sulfides with pyrone, enantioselectivity of)
     54761-04-5
ΤТ
     RL: CAT (Catalyst use); USES (Uses)
        (catalyst, for inverse electron-demand Diels-Alder cycloaddn. of vinyl
        ethers or sulfides with pyrone, enantioselectivity of)
ΙT
     25991-27-9, 3-Carbomethoxy-2-pyrone
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (catalytic inverse electron-demand Diels-Alder cycloaddn. with ethers
        and sulfides, enantioselectivity of)
     109-92-2, Ethyl vinyl ether 111-34-2, Butyl vinyl ether
ΤT
                                                        1191-99-7,
     Ethyl vinyl sulfide 935-04-6, Benzyl vinyl ether
     2,3-Dihydrofuran 1822-73-7, Phenyl vinyl sulfide
                                                          1822-76-0, Benzvl
     vinyl sulfide
                   2182-55-0, Cyclohexyl vinyl ether
                                                         4789-70-2, Butyl
vinvl
    sulfide
              18888-48-7, Cyclohexyl vinyl sulfide
                                                     22881-48-7
     42459-51-8
    RL: RCT (Reactant); RACT (Reactant or reagent)
        (catalytic inverse electron-demand Diels-Alder cycloaddn. with pyrone
        of, enantioselectivity of)
     156724-93-5P 156724-94-6P 156724-95-7P
                                                  156724-96-8P
TΤ
                                                                 156724-97-9P
     156724-98-0P
                  156724-99-1P
                                  156725-00-7P
                                                  156725-01-8P
                                                                 156725-02-9P
     156725-03-0P
                  156725-04-1P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (preparation of, by catalytic inverse electron-demand Diels-Alder
        of pyrone with vinyl ethers or sulfides, enantioselectivity of)
L12 ANSWER 11 OF 11 CAPLUS COPYRIGHT 2008 ACS on STN
    1973:405820 CAPLUS
DN
    79:5820
OREF 79:983a,986a
     Entered STN: 12 May 1984
    Synthesis and polymerization of vinyl esters and vinyl ethers having
ΤI
bulky
     substituents
     Nozakura, Shun-ichi; Okamoto, Takehiko; Toyora, Kunimitsu; Murahashi,
ΑU
CS
    Fac. Sci., Osaka Univ., Toyonaka, Japan
     Journal of Polymer Science, Polymer Chemistry Edition (1973), 11(5),
SO
     1043-51
    CODEN: JPLCAT; ISSN: 0449-296X
DT
    Journal
LA
    English
CC
     35-6 (Synthetic High Polymers)
```

```
The bulky adamantyl group in vinyl ester monomers favored the formation
AΒ
\circf
     syndiotactic polymers, whereas in the vinyl ether monomers it favored
     isotacticity when polymerized in nonpolar solvents. As open-chain
models of
     vinyl adamantyl monomers, vinyl trialkylcarbinyl esters were prepared and
    polymerized to give syndiotactic polymers. Vinyl tripropylcarbinyl ether
     [40762-65-0] gave heterotactic polymer. Tacticities were determined
from the
     ir spectra of poly(vinyl alc.) [9002-89-5] prepared by reduction of the
polymers
    with LiAlH4.
ST
    polyvinyl adamantylcarboxylate tacticity; stereoregularity polyvinyl
     ester; ester isotacticity polyvinyl; adamantyl ether polymer tacticity;
     vinyl ether polymer tacticity
ΙT
    Polymerization
        (cationic and radical, of vinyl esters and ethers, tacticity in)
ΤT
     Tacticity
        (of vinyl ester and ether polymers, substituent effects on)
ΙT
     Substituent effect
        (on tacticity, of vinyl ester and ether polymers)
                   40762-65-0P
                                42459-47-2P
                                              42459-48-3P
                                                              42459-49-4P
IT
     16917-72-9P
     42459-51-8P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (preparation of)
ΙT
     26715-88-8
                  42439-69-0
                               42439-70-3
                                           42439-71-4
                                                         42439-72-5
     42439-73-6
                  42439-74-7
    RL: PRP (Properties)
        (tacticity of, determination of)
TΤ
     74-86-2, reactions
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (vinylation by, of alcs.)
TΤ
     2198-72-3
                 2819-03-6
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (vinylation of, by acetylene)
=> d his
     (FILE 'HOME' ENTERED AT 14:59:26 ON 14 FEB 2008)
    FILE 'REGISTRY' ENTERED AT 14:59:37 ON 14 FEB 2008
              1 S 42459-51-8
L1
              3 S ADAMANTOL
L2
            564 S ADAMANT AND OL
L3
            564 S L3
L4
              0 S ADAMANT ADJ 1 ADJ OL
L5
L6
            564 S ADAMANT AND OL
L7
              0 S C10H16O/MFW
           5733 S C10H16O/MF
L8
L9
              2 S L8 AND L6
L10
              1 S 768-95-6
     FILE 'CAPLUS' ENTERED AT 15:03:21 ON 14 FEB 2008
T.11
           1659 S L10 OR L1
```

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FOR 10/553083 by Cynthia Hamilton
             11 S L1
L12
=> s 111 and ((chem? and ampli?) or positiv? or photo?)
       2882437 CHEM?
        422323 AMPLI?
        123964 POSITIV?
       1552780 PHOTO?
L13
           131 L11 AND ((CHEM? AND AMPLI?) OR POSITIV? OR PHOTO?)
=> s 113 and ( (POLYHYDROXYSTYRENE? OR POLY HYDROXYSTYRENE? OR POLY HYDROXY
STYRENE? OR POLYHYDROXY STYRENE? OR POLYVINYLPHENOL? OR POLYVINYL PHENOL?
OR POLY VINYL PHENOL? OR POLY VINYLPHENOL?))
          1081 POLYHYDROXYSTYRENE?
        726508 POLY
          3434 HYDROXYSTYRENE?
           858 POLY HYDROXYSTYRENE?
                 (POLY(W)HYDROXYSTYRENE?)
        726508 POLY
        466398 HYDROXY
        307853 STYRENE?
            24 POLY HYDROXY STYRENE?
                 (POLY (W) HYDROXY (W) STYRENE?)
          7256 POLYHYDROXY
        307853 STYRENE?
            24 POLYHYDROXY STYRENE?
                (POLYHYDROXY(W)STYRENE?)
           919 POLYVINYLPHENOL?
        102645 POLYVINYL
        445745 PHENOL?
           188 POLYVINYL PHENOL?
                 (POLYVINYL(W)PHENOL?)
        726508 POLY
        427568 VINYL
        445745 PHENOL?
           255 POLY VINYL PHENOL?
                 (POLY(W)VINYL(W)PHENOL?)
        726508 POLY
          2991 VINYLPHENOL?
           845 POLY VINYLPHENOL?
                 (POLY(W)VINYLPHENOL?)
L14
             2 L13 AND ( (POLYHYDROXYSTYRENE? OR POLY HYDROXYSTYRENE? OR
POLY
                HYDROXY STYRENE? OR POLYHYDROXY STYRENE? OR
POLYVINYLPHENOL?
               OR POLYVINYL PHENOL? OR POLY VINYL PHENOL? OR POLY
VINYLPHEN
              OL?))
=> d all 1-2
L14 ANSWER 1 OF 2 CAPLUS COPYRIGHT 2008 ACS on STN
AN
     2002:347843 CAPLUS
DN
     136:361825
ED
     Entered STN: 09 May 2002
ΤI
     Ionizing radiation-sensitive chemically amplified
```

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resolution,
    and their use
IN
    Namiki, Takahisa; Yano, Akira; Kon, Junichi; Nozaki, Koji; Ozawa, Miwa
    Fujitsu Ltd., Japan
    Jpn. Kokai Tokkyo Koho, 13 pp.
    CODEN: JKXXAF
DT
   Patent
LA
   Japanese
IC
    ICM G03F007-038
        C08K005-101; C08K005-1545; C08K005-42; C08K005-51; C08K005-52;
         C08L101-02; G03F007-004; H01L021-027
    74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
CC
    Reprographic Processes)
FAN.CNT 1
    PATENT NO.
                      KIND DATE
                                        APPLICATION NO.
                                                               DATE
                              _____
                       ____
                                          _____
                       А
                             20020509 JP 2000-322374
                                                              20001023
    JP 2002131909
PRAI JP 2000-322374
                              20001023
CLASS
PATENT NO. CLASS PATENT FAMILY CLASSIFICATION CODES
 -----
                      ______
JP 2002131909
                ICM
                      G03F007-038
                ICS
                      C08K005-101; C08K005-1545; C08K005-42; C08K005-51;
                      C08K005-52; C08L101-02; G03F007-004; H01L021-027
                IPCI
                      G03F0007-038 [ICM, 7]; C08K0005-101 [ICS, 7];
                      C08K0005-1545 [ICS, 7]; C08K0005-42 [ICS, 7];
C08K0005-51
                       [ICS, 7]; C08K0005-52 [ICS, 7]; C08K0005-00 [ICS, 7, C*];
                      C08L0101-02 [ICS, 7]; C08L0101-00 [ICS, 7, C*];
                      G03F0007-004 [ICS,7]; H01L0021-027 [ICS,7];
H01L0021-02
                      [ICS, 7, C*]
                IPCR
                      G03F0007-038 [I,C*]; G03F0007-038 [I,A]; C08K0005-00
                      [I,C*]; C08K0005-101 [I,A]; C08K0005-1545 [I,A];
                      C08K0005-42 [I,A]; C08K0005-51 [I,A]; C08K0005-52
                       [I,A]; C08L0101-00 [I,C*]; C08L0101-02 [I,A];
                      G03F0007-004 [I,C*]; G03F0007-004 [I,A]; H01L0021-02
                       [I,C*]; H01L0021-027 [I,A]
OS
    MARPAT 136:361825
AB
    The compns. comprise (A) ionizing radiation-sensitive acid generators,
(B)
    alkali-soluble resist materials, which become alkali-insol. in the
presence
    of acids, and (C) additives forming free acid groups selected from
    carboxyl, sulfonic, and phosphoric acids by opening intramol. esters in
    the presence of alkali developing agents. The additives increase
    alkali-solubility of non-exposed areas.
ST
    neg photoresist phenolphthalein chem
    amplification sensitivity; ionizing radiation resist resoln alkali
    developing
ΙT
    Phenolic resins, preparation
    RL: IMF (Industrial manufacture); POF (Polymer in formulation); TEM
     (Technical or engineered material use); PREP (Preparation); USES (Uses)
       (aminoplast-, novolak; chemical amplified neg.
```

negative-working resist compositions with high sensitivity and

```
photoresists with high sensitivity and resolution using free acid
        group-forming additives)
ΙT
     Epoxy resins, uses
    RL: POF (Polymer in formulation); TEM (Technical or engineered material
     use); USES (Uses)
        (chemical amplified neg. photoresists with
        high sensitivity and resolution using free acid group-forming
additives)
    Resists
        (neg.-working radiation-sensitive; chemical amplified
        neg. photoresists with high sensitivity and resolution using
        free acid group-forming additives)
ΤТ
     Aminoplasts
    RL: IMF (Industrial manufacture); POF (Polymer in formulation); TEM
     (Technical or engineered material use); PREP (Preparation); USES (Uses)
        (phenolic, novolak; chemical amplified neg.
        photoresists with high sensitivity and resolution using free acid
        group-forming additives)
     77-09-8, Phenolphthalein
                               143-74-8
                                           2321-07-5
     RL: CPS (Chemical process); MOA (Modifier or additive use); PEP
(Physical,
     engineering or chemical process); TEM (Technical or engineered material
     use); PROC (Process); USES (Uses)
        (additives forming free acid groups; chemical amplified
        neg. photoresists with high sensitivity and resolution using
        free acid group-forming additives)
ΙT
    76-09-5, Pinacol 108-78-1, Melamine, uses 768-95-6,
     1-Adamantanol
     RL: TEM (Technical or engineered material use); USES (Uses)
        (alkali-insolubilizing resist polymers with; chemical
        amplified neg. photoresists with high sensitivity and
        resolution using free acid group-forming additives)
ΤT
     54243-98-0P, Cresol-formaldehyde-melamine copolymer 420124-57-8P,
    Melamine-vinylphenol copolymer
     RL: IMF (Industrial manufacture); POF (Polymer in formulation); TEM
     (Technical or engineered material use); PREP (Preparation); USES (Uses)
        (chemical amplified neg. photoresists with
        high sensitivity and resolution using free acid group-forming
additives)
     9016-83-5, Cresol-formaldehyde copolymer
                                                59269-51-1, Polyvinyl
    phenol
    RL: POF (Polymer in formulation); TEM (Technical or engineered material
     use); USES (Uses)
        (chemical amplified neg. photoresists with
        high sensitivity and resolution using free acid group-forming
additives)
L14 ANSWER 2 OF 2 CAPLUS COPYRIGHT 2008 ACS on STN
     1997:471370 CAPLUS
ΑN
DN
     127:176770
     Entered STN: 26 Jul 1997
ED
ΤI
    Synthesis and dissolution characteristics of novel alicyclic polymers
with
    monoacid ester structures
ΑIJ
    Hattori, Takashi; Tsuchiya, Yuko; Yamanaka, Ryoko; Hattori, Keiko;
```

Shiraishi, Hiroshi

- CS Central Research Laboratory, Hitachi Ltd., Kokubunji, 185, Japan
- SO Journal of Photopolymer Science and Technology (1997), 10(4), 535-544 CODEN: JSTEEW; ISSN: 0914-9244
- PB Technical Association of Photopolymers, Japan
- DT Journal
- LA English
- CC 35-4 (Chemistry of Synthetic High Polymers)
 Section cross-reference(s): 36, 37
- AB Novel alicyclic polymers having monoacid ester structures were prepared by

alcoholysis of non-conjugated cyclic diene and maleic anhydride copolymers. This polymer, named ALPHA, exhibited good solubility (10-50 nm/s)

in 0.113% aqueous tetramethyl-ammonium hydroxide solution without swelling.

Absorbance was around 0.6 $\mu m-1$ at 193 nm. Dry-etching resistance for C12/BC13 gas was the same as that of polyhydroxystyrene. A two-component resist system, consisting of 1-ethoxyethyl-protected ALPHA polymer and onium salt, produced 0.20- μm line-and-space patterns using a KrF excimer laser stepper with a phase-shifting mask. ALPHA is suitable

as a base polymer for ArF excimer laser resists.

- ST alicyclic polymer monoacid ester prepn dissoln; cyclic diene maleic anhydride copolymer alcoholysis; dry etching resistance alicyclic polymer ester; argon fluoride excimer laser resist
- IT Etching

 $(\hbox{dry-etching resistance of novel alicyclic polymers with monoacid} \\$

structures under Cl2/BCl2 gas conditions)

IT Alcoholysis

Polymerization

(in synthesis of novel alicyclic polymers with monoacid ester structures) $\$

IT Dissolution rate

Photoresists

(synthesis and dissoln. characteristics of novel alicyclic polymers with monoacid ester structures)

IT 7782-50-5, Chlorine, miscellaneous 13842-52-9, Boron dichloride RL: MSC (Miscellaneous)

 $\hbox{ (dry-etching resistance of novel alicyclic polymers with monoacid ester } \\$

structures under C12/BC12 gas conditions)

64-17-5DP, Ethanol, reaction products with cyclic diene-maleic anhydride ΤТ copolymer, preparation 67-56-1DP, Methanol, reaction products with cyclic diene-maleic anhydride copolymer, preparation 67-63-0DP, 2-Propanol, reaction products with cyclic diene-maleic anhydride copolymer, preparation 109-92-2DP, Ethyl vinyl ether, reaction products with cyclic diene-maleic anhydride copolymer 768-95-6DP, 1-Adamantanol, reaction products with cyclic diene-maleic anhydride 4442-79-9DP, 2-Cyclohexylethanol, reaction products with copolymer cyclic diene-maleic anhydride copolymer 5240-72-2DP, Norbornane-2-methanol, reaction products with cyclic diene-maleic anhydride copolymer 25212-41-3DP, Cycloocta-1,5-diene-maleic anhydride copolymer, alc.-hydrolyzed 25212-41-3P, Cycloocta-1,5-diene-maleic

```
28132-01-6DP,
     anhydride copolymer
4,8-Bis(hydroxymethyl)tricyclo[5.2.1.0
     2,6]decane, reaction products with cyclic diene-maleic anhydride
copolymer
     30600-22-7DP, Maleic anhydride-5-methylenebicyclo[2.2.1]-2-heptene
     copolymer, alc.-hydrolyzed 30600-22-7P, Maleic anhydride-5-
    methylenebicyclo[2.2.1]-2-heptene copolymer 34011-82-0DP,
     5-Ethylenebicyclo[2.2.1]-2-heptene-maleic anhydride copolymer,
     alc.-hydrolyzed 34011-82-0P, 5-Ethylenebicyclo[2.2.1]-2-heptene-maleic
     anhydride copolymer 34149-10-5DP, Maleic
anhydride-5-vinylbicyclo[2.2.1]-
     2-heptene copolymer, alc.-hydrolyzed
                                          34149-10-5P, Maleic
     anhydride-5-vinylbicyclo[2.2.1]-2-heptene copolymer
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (synthesis and dissoln. characteristics of novel alicyclic polymers
       with monoacid ester structures)
=> d his
     (FILE 'HOME' ENTERED AT 14:59:26 ON 14 FEB 2008)
    FILE 'REGISTRY' ENTERED AT 14:59:37 ON 14 FEB 2008
             1 S
                  42459-51-8
L1
L2
             3 S ADAMANTOL
L3
           564 S ADAMANT AND OL
L4
           564 S L3
L5
             0 S ADAMANT ADJ 1 ADJ OL
           564 S ADAMANT AND OL
L6
L7
             0 S C10H16O/MFW
          5733 S C10H16O/MF
L8
L9
             2 S L8 AND L6
L10
             1 S 768-95-6
    FILE 'CAPLUS' ENTERED AT 15:03:21 ON 14 FEB 2008
L11
          1659 S L10 OR L1
L12
            11 S L1
L13
           131 S L11 AND ((CHEM? AND AMPLI?) OR POSITIV? OR PHOTO?)
L14
             2 S L13 AND ( (POLYHYDROXYSTYRENE? OR POLY HYDROXYSTYRENE? OR
PO
=> log y
COST IN U.S. DOLLARS
                                                 SINCE FILE
                                                                TOTAL
                                                     ENTRY
                                                              SESSION
                                                              174.19
FULL ESTIMATED COST
                                                      88.27
DISCOUNT AMOUNTS (FOR QUALIFYING ACCOUNTS)
                                                SINCE FILE
                                                                TOTAL
                                                     ENTRY
                                                              SESSION
CA SUBSCRIBER PRICE
                                                      -10.40
                                                               -10.40
```

STN INTERNATIONAL LOGOFF AT 15:07:47 ON 14 FEB 2008

Connecting via Winsock to STN

Welcome to STN International! Enter x:x

LOGINID: SSSPTAU156CXH

PASSWORD:

TERMINAL (ENTER 1, 2, 3, OR ?):2

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* * * * * * * * *
                     Welcome to STN International
NEWS
                 Web Page for STN Seminar Schedule - N. America
NEWS
         AUG 06
                 CAS REGISTRY enhanced with new experimental property tags
NEWS 3
         AUG 06 FSTA enhanced with new thesaurus edition
NEWS 4 AUG 13
                 CA/CAplus enhanced with additional kind codes for granted
                 patents
NEWS
         AUG 20
                 CA/CAplus enhanced with CAS indexing in pre-1907 records
                 Full-text patent databases enhanced with predefined
NEWS
         AUG 27
                 patent family display formats from INPADOCDB
         AUG 27
                 USPATOLD now available on STN
NEWS
      8 AUG 28
NEWS
                 CAS REGISTRY enhanced with additional experimental
                 spectral property data
NEWS 9 SEP 07
                 STN AnaVist, Version 2.0, now available with Derwent
                 World Patents Index
NEWS 10 SEP 13 FORIS renamed to SOFIS
NEWS 11 SEP 13
                 INPADOCDB enhanced with monthly SDI frequency
NEWS 12 SEP 17
                 CA/CAplus enhanced with printed CA page images from
                 1967-1998
         SEP 17
                 CAplus coverage extended to include traditional medicine
NEWS 13
                 patents
NEWS 14 SEP 24
                 EMBASE, EMBAL, and LEMBASE reloaded with enhancements
NEWS 15 OCT 02 CA/Caplus enhanced with pre-1907 records from Chemisches
                 Zentralblatt
NEWS 16 OCT 19 BEILSTEIN updated with new compounds
NEWS 17 NOV 15 Derwent Indian patent publication number format enhanced
NEWS 18 NOV 19 WPIX enhanced with XML display format
NEWS 19 NOV 30 ICSD reloaded with enhancements
NEWS 20 DEC 04 LINPADOCDB now available on STN
NEWS 21 DEC 14 BEILSTEIN pricing structure to change
NEWS 22 DEC 17 USPATOLD added to additional database clusters
         DEC 17 IMSDRUGCONF removed from database clusters and STN
NEWS 23
         DEC 17 DGENE now includes more than 10 million sequences
NEWS 24
NEWS 25
         DEC 17 TOXCENTER enhanced with 2008 MeSH vocabulary in
                 MEDLINE segment
         DEC 17
NEWS 26
                 MEDLINE and LMEDLINE updated with 2008 MeSH vocabulary
         DEC 17
NEWS 27
                 CA/CAplus enhanced with new custom IPC display formats
NEWS 28
         DEC 17
                 STN Viewer enhanced with full-text patent content
                 from USPATOLD
NEWS 29
         JAN 02
                 STN pricing information for 2008 now available
NEWS 30
         JAN 16
                 CAS patent coverage enhanced to include exemplified
                 prophetic substances
NEWS 31
        JAN 28
                 USPATFULL, USPAT2, and USPATOLD enhanced with new
```

custom IPC display formats

NEWS 32 JAN 28 MARPAT searching enhanced

NEWS 33 JAN 28 USGENE now provides USPTO sequence data within 3 days of publication

NEWS 34 JAN 28 TOXCENTER enhanced with reloaded MEDLINE segment

NEWS 35 JAN 28 MEDLINE and LMEDLINE reloaded with enhancements

NEWS 36 FEB 08 STN Express, Version 8.3, now available

NEWS EXPRESS FEBRUARY 08 CURRENT WINDOWS VERSION IS V8.3,
AND CURRENT DISCOVER FILE IS DATED 24 JANUARY 2008

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NEWS IPC8 For general information regarding STN implementation of IPC 8

Enter NEWS followed by the item number or name to see news on that specific topic.

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FILE 'HOME' ENTERED AT 16:10:07 ON 14 FEB 2008

=> FILE REG

COST IN U.S. DOLLARS

SINCE FILE TOTAL ENTRY SESSION 0.21 0.21

FULL ESTIMATED COST

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Property values tagged with IC are from the ${\tt ZIC/VINITI}$ data file provided by InfoChem.

STRUCTURE FILE UPDATES: 13 FEB 2008 HIGHEST RN 1003293-96-6 DICTIONARY FILE UPDATES: 13 FEB 2008 HIGHEST RN 1003293-96-6

New CAS Information Use Policies, enter HELP USAGETERMS for details.

TSCA INFORMATION NOW CURRENT THROUGH June 29, 2007

Please note that search-term pricing does apply when conducting ${\tt SmartSELECT}$ searches.

REGISTRY includes numerically searchable data for experimental and predicted properties as well as tags indicating availability of experimental property data in the original document. For information

on property searching in REGISTRY, refer to:

http://www.cas.org/support/stngen/stndoc/properties.html

=> S 768-95-6

L1 1 768-95-6

(768-95-6/RN)

=> S 768-95-6/CRN

L2 127 768-95-6/CRN

=> FILE CAPLUS

COST IN U.S. DOLLARS

SINCE FILE TOTAL ENTRY SESSION

0.67

FULL ESTIMATED COST 0.46

FILE 'CAPLUS' ENTERED AT 16:10:54 ON 14 FEB 2008
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FILE COVERS 1907 - 14 Feb 2008 VOL 148 ISS 7 FILE LAST UPDATED: 13 Feb 2008 (20080213/ED)

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http://www.cas.org/infopolicy.html

=> S L1 OR L2

1652 L1

93 L2

L3 1717 L1 OR L2

=> S L3 AND PHOTO?

1552780 PHOTO?

L4 130 L3 AND PHOTO?

=> S L3 AND CHEM? AND AMPLI?

2882437 CHEM?

422323 AMPLI?

L5 7 L3 AND CHEM? AND AMPLI?

=> D ALL 1-7

```
ANSWER 1 OF 7 CAPLUS COPYRIGHT 2008 ACS on STN
L5
   2007:593411 CAPLUS
AN
DN
   147:42228
   Entered STN: 01 Jun 2007
ED
TI Salt suitable for an acid generator and a chemically
    amplified photoresist composition containing the same
    Yamaguchi, Satoshi; Harada, Yukako; Yoshida, Isao
ΤN
    Sumitomo Chemical Company, Limited, Japan
   U.S. Pat. Appl. Publ., 35pp.
    CODEN: USXXCO
DT
   Patent
   English
LA
INCL 430311000; 560150000; 558408000
    74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
    Reprographic Processes)
FAN.CNT 1
    PATENT NO.
                    KIND DATE
                                     APPLICATION NO.
                                                          DATE
                     ----
                            _____
     _____
                                      _____
20061117
                                                           20061117
                                                           20061117
CLASS
PATENT NO. CLASS PATENT FAMILY CLASSIFICATION CODES
 US 2007122750 INCL 430311000; 560150000; 558408000
              IPCI G03C0005-00 [I,A]; C07C0309-12 [I,A]; C07C0309-00
                     [I,C*]
                     430/311.000; 560/150.000; 558/408.000
              NCL
 KR 2007053619
              IPCI C07C0309-65 [I,A]; C07C0309-74 [I,A]; C07C0309-00
                     [I,C*]; C07C0321-24 [I,A]; C07C0321-00 [I,C*]
 CN 1971421
              IPCI
                    G03F0007-039 [I,A]
 [I,A]; C08L0101-02 [I,A]; C08L0101-00 [I,C*];
                     C08K0005-42 [I,A]; C08K0005-00 [I,C*]; C07C0309-17
                     [I,A]; C07C0309-00 [I,C*]; C07C0303-22 [I,A];
                     C07C0303-00 [I,C*]; C07D0333-46 [I,A]; C07D0333-00
                     [I,C*]; C07B0061-00 [N,A]
               FTERM 2H025/AA02; 2H025/AB16; 2H025/AC04; 2H025/AC08;
                     2H025/BE07; 2H025/BE10; 2H025/BG00; 2H025/CB14;
                     2H025/CB41; 2H025/FA17; 4H006/AA01; 4H006/AA02;
                     4H006/AA03; 4H006/AB81; 4H006/AC48; 4H006/BA52;
                     4H006/BA66; 4H006/BB12; 4H006/BB15; 4H006/BB17;
                     4H006/BB21; 4H039/CA66; 4H039/CD30; 4J002/BC041;
                     4J002/BG041; 4J002/BG051; 4J002/BH021; 4J002/BK002;
                     4J002/EV256; 4J002/FD206; 4J002/GP03
    MARPAT 147:42228
OS
GΙ
```

AB The present invention provides a salt of the formula I: wherein ring X represents monocyclic or polycyclic hydrocarbon group having 3 to 30 carbon atoms, and one or more hydrogen atom in the monocyclic or polycyclic hydrocarbon group is optionally substituted with alkyl group having 1 to 10 carbon atom, alkoxy group having 1 to 10 carbon atom, perfluoroalkyl group having 1 to 4 carbon atoms, hydroxyalkyl group having

1 to 10 carbon atoms or cyano group; Q1 and Q2 each independently represent fluorine atom or perfluoroalkyl group having 1 to 6 carbon atoms; and A+ represents organic counter ion. The present invention also provides a chemical amplified resist composition comprising the salt of the formula I.

ST photoacid generator chem amplified photoresist lithog

IT Photoresists

(salt of photoacid generator for chemical amplified resist)

IT 19158-66-8P 938447-98-4P 938448-03-4P 938448-04-5P 938448-08-9P 938448-12-5P

RL: IMF (Industrial manufacture); PRP (Properties); RCT (Reactant); PREP (Preparation); RACT (Reactant or reagent)

(salt of photoacid generator for chemical amplified resist)

IT 938448-02-3P 938448-06-7P 938448-07-8P 938448-10-3P 938448-11-4P 938448-14-7P

RL: IMF (Industrial manufacture); PRP (Properties); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(salt of photoacid generator for chemical amplified resist)

IT 912289-98-6P

RL: IMF (Industrial manufacture); RCT (Reactant); PREP (Preparation);

RACT

(Reactant or reagent)

(salt of photoacid generator for chemical amplified resist)

IT 938448-00-1P 938448-15-8P

RL: IMF (Industrial manufacture); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(salt of photoacid generator for chemical amplified resist)

IT 70-11-1 96-41-3, Cyclopentanol 108-93-0, Cyclohexanol, reactions 110-01-0 360-68-9 680-15-9 700-57-2, Tricyclo[3.3.1.13,7]decan-2-ol 768-95-6, Tricyclo[3.3.1.13,7]decan-1-ol 4270-70-6

RL: RCT (Reactant); RACT (Reactant or reagent)

(salt of photoacid generator for chemical amplified resist)

IT 258879-87-7

RL: TEM (Technical or engineered material use); USES (Uses)

(salt of photoacid generator for chemical amplified resist)

- L5 ANSWER 2 OF 7 CAPLUS COPYRIGHT 2008 ACS on STN
- AN 2006:485754 CAPLUS
- DN 144:477829
- ED Entered STN: 25 May 2006
- TI Fluorine-containing polymers, their preparation, and resist compositions therewith
- IN Yokokoji, Osamu; Sasaki, Takashi; Wang, Shu Zhong
- PA Asahi Glass Co., Ltd., Japan
- SO Jpn. Kokai Tokkyo Koho, 36 pp. CODEN: JKXXAF
- DT Patent
- LA Japanese
- CC 74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other Reprographic Processes)

Section cross-reference(s): 37

FAN.CNT 1

PATENT NO.	KIND	DATE	APPLICATION NO.	DATE
PI JP 2006131879	A	20060525	JP 2005-208683	20050719
PRAI JP 2004-291376	A	20041004		
CLASS				

PATENT NO. CLASS PATENT FAMILY CLASSIFICATION CODES

JP 2006131879 IPCI C08F0220-22 [I,A]; C08F0220-28 [I,A]; C08F0220-00

[I,C*]; G03F0007-039 [I,A]; H01L0021-027 [I,A];

H01L0021-02 [I,C*]

FTERM 2H025/AA01; 2H025/AA02; 2H025/AB16; 2H025/AC04; 2H025/AC08; 2H025/AD03; 2H025/BE00; 2H025/BE10; 2H025/BG00; 2H025/CB14; 2H025/CB41; 2H025/CB45; 2H025/CC03; 2H025/FA10; 2H025/FA17; 4J100/AL03Q; 4J100/AL04Q; 4J100/AL08P; 4J100/AL08Q; 4J100/AL26P; 4J100/BA03P; 4J100/BA03Q; 4J100/BA05Q; 4J100/BB07P; 4J100/BB11P; 4J100/BB18P; 4J100/BB18Q; 4J100/BC03Q; 4J100/BC04Q; 4J100/BC07P; 4J100/BC07Q; 4J100/CA04;

4J100/JA38

GI

$$CX_{2} CX_{2} CHF$$

$$CX_{2} CX_{2} CHF$$

$$CX_{2} CX_{2} CX_{2}$$

```
The polymers are prepared from I (R1 = H, Me, F, CF3; Y = H, F, OH; X =
AΒ
Η,
     F) and CH2:CR2CO2R3 [R2 = H, F, C\leq3 (fluoro)alkyl; R3 = C\leq20
    monovalent organic group]. The photoresists contain the polymers,
    generators, and organic solvents.
    photoresist hydroperfluoroadamantyl methacrylate polymer exposure light
    transparency; methacryloyloxyperfluoroadamantane butyrolactone
    methacrylate copolymer amplified photoresist functionality concn
ΙT
    Positive photoresists
        (chemical amplified; fluoropolymers with high concentration
        of functional groups for resists transparent to lights over wide
        wavelength range)
     160823-54-1P
                   160823-55-2P
                                   160823-57-4P
                                                  558482-16-9P
ΙT
                                                                  558482-17-0P
     558482-22-7P
                   849065-98-1P
                                   872205-43-1P
                                                  872205-49-7P
                                                                  872205-50-0P
                   886845-86-9P
                                   886845-87-0P
                                                  886845-88-1P
     886845-85-8P
                                                                  886845-89-2P
     886845-90-5P
     RL: IMF (Industrial manufacture); RCT (Reactant); PREP (Preparation);
RACT
     (Reactant or reagent)
        (fluoropolymers with high concentration of functional groups for
resists
        transparent to lights over wide wavelength range)
                  886845-84-7P
                                 886845-91-6P
                                                 886845-92-7P
TΤ
     886845-83-6P
     RL: IMF (Industrial manufacture); TEM (Technical or engineered material
     use); PREP (Preparation); USES (Uses)
        (fluoropolymers with high concentration of functional groups for
resists
        transparent to lights over wide wavelength range)
     677-84-9, Perfluoroisobutyryl fluoride 768-95-6,
TΤ
     1-Hydroxyadamantane
                           5001-18-3, 1,3-Adamantanediol 99181-50-7,
     1,3,5-Adamantanetriol
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (fluoropolymers with high concentration of functional groups for
resists
        transparent to lights over wide wavelength range)
     872205-53-3P 872205-54-4P
     RL: IMF (Industrial manufacture); RCT (Reactant); PREP (Preparation);
RACT
     (Reactant or reagent)
        (monomers; fluoropolymers with high concentration of functional
groups for
        resists transparent to lights over wide wavelength range)
ΤТ
     66003-78-9, Triphenylsulfonium triflate
     RL: CAT (Catalyst use); TEM (Technical or engineered material use); USES
     (Uses)
        (photoacid generators; fluoropolymers with high concentration of
functional
        groups for resists transparent to lights over wide wavelength range)
     ANSWER 3 OF 7 CAPLUS COPYRIGHT 2008 ACS on STN
T<sub>1</sub>5
     2002:347843 CAPLUS
ΑN
     136:361825
DΝ
ED
     Entered STN: 09 May 2002
ΤI
     Ionizing radiation-sensitive chemically amplified
```

resolution,

and their use

```
IN
    Namiki, Takahisa; Yano, Akira; Kon, Junichi; Nozaki, Koji; Ozawa, Miwa
    Fujitsu Ltd., Japan
    Jpn. Kokai Tokkyo Koho, 13 pp.
    CODEN: JKXXAF
DT
   Patent
LA
   Japanese
IC
    ICM G03F007-038
        C08K005-101; C08K005-1545; C08K005-42; C08K005-51; C08K005-52;
         C08L101-02; G03F007-004; H01L021-027
    74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
CC
    Reprographic Processes)
FAN.CNT 1
    PATENT NO.
                      KIND DATE
                                        APPLICATION NO.
                                                               DATE
                              _____
                       ____
                                          _____
                       А
                             20020509 JP 2000-322374
                                                              20001023
    JP 2002131909
PRAI JP 2000-322374
                              20001023
CLASS
PATENT NO. CLASS PATENT FAMILY CLASSIFICATION CODES
 -----
                      ______
JP 2002131909
                ICM
                      G03F007-038
                ICS
                      C08K005-101; C08K005-1545; C08K005-42; C08K005-51;
                      C08K005-52; C08L101-02; G03F007-004; H01L021-027
                IPCI
                      G03F0007-038 [ICM, 7]; C08K0005-101 [ICS, 7];
                      C08K0005-1545 [ICS, 7]; C08K0005-42 [ICS, 7];
C08K0005-51
                       [ICS, 7]; C08K0005-52 [ICS, 7]; C08K0005-00 [ICS, 7, C*];
                      C08L0101-02 [ICS, 7]; C08L0101-00 [ICS, 7, C*];
                      G03F0007-004 [ICS,7]; H01L0021-027 [ICS,7];
H01L0021-02
                      [ICS, 7, C*]
                IPCR
                      G03F0007-038 [I,C*]; G03F0007-038 [I,A]; C08K0005-00
                      [I,C*]; C08K0005-101 [I,A]; C08K0005-1545 [I,A];
                      C08K0005-42 [I,A]; C08K0005-51 [I,A]; C08K0005-52
                       [I,A]; C08L0101-00 [I,C*]; C08L0101-02 [I,A];
                      G03F0007-004 [I,C*]; G03F0007-004 [I,A]; H01L0021-02
                       [I,C*]; H01L0021-027 [I,A]
OS
    MARPAT 136:361825
    The compns. comprise (A) ionizing radiation-sensitive acid generators,
AB
(B)
    alkali-soluble resist materials, which become alkali-insol. in the
presence
    of acids, and (C) additives forming free acid groups selected from
    carboxyl, sulfonic, and phosphoric acids by opening intramol. esters in
    the presence of alkali developing agents. The additives increase
    alkali-solubility of non-exposed areas.
ST
    neg photoresist phenolphthalein chem amplification
    sensitivity; ionizing radiation resist resoln alkali developing
ΙT
    Phenolic resins, preparation
    RL: IMF (Industrial manufacture); POF (Polymer in formulation); TEM
     (Technical or engineered material use); PREP (Preparation); USES (Uses)
       (aminoplast-, novolak; chemical amplified neg.
       photoresists with high sensitivity and resolution using free acid
```

negative-working resist compositions with high sensitivity and

```
group-forming additives)
ΤТ
     Epoxy resins, uses
     RL: POF (Polymer in formulation); TEM (Technical or engineered material
     use); USES (Uses)
        (chemical amplified neg. photoresists with high
        sensitivity and resolution using free acid group-forming additives)
ΙT
        (neg.-working radiation-sensitive; chemical amplified
        neg. photoresists with high sensitivity and resolution using free acid
        group-forming additives)
ΙT
    Aminoplasts
    RL: IMF (Industrial manufacture); POF (Polymer in formulation); TEM
     (Technical or engineered material use); PREP (Preparation); USES (Uses)
        (phenolic, novolak; chemical amplified neg.
        photoresists with high sensitivity and resolution using free acid
        group-forming additives)
     77-09-8, Phenolphthalein
                               143-74-8
                                           2321-07-5
     RL: CPS (Chemical process); MOA (Modifier or additive use); PEP
(Physical,
     engineering or chemical process); TEM (Technical or engineered material
     use); PROC (Process); USES (Uses)
        (additives forming free acid groups; chemical amplified
        neg. photoresists with high sensitivity and resolution using free acid
        group-forming additives)
ΙT
     76-09-5, Pinacol
                       108-78-1, Melamine, uses 768-95-6,
     1-Adamantanol
     RL: TEM (Technical or engineered material use); USES (Uses)
        (alkali-insolubilizing resist polymers with; chemical
        amplified neg. photoresists with high sensitivity and resolution
        using free acid group-forming additives)
ΙT
     54243-98-0P, Cresol-formaldehyde-melamine copolymer
                                                           420124-57-8P,
    Melamine-vinylphenol copolymer
     RL: IMF (Industrial manufacture); POF (Polymer in formulation); TEM
     (Technical or engineered material use); PREP (Preparation); USES (Uses)
        (chemical amplified neg. photoresists with high
        sensitivity and resolution using free acid group-forming additives)
ΙT
     9016-83-5, Cresol-formaldehyde copolymer 59269-51-1, Polyvinyl phenol
     RL: POF (Polymer in formulation); TEM (Technical or engineered material
     use); USES (Uses)
        (chemical amplified neg. photoresists with high
        sensitivity and resolution using free acid group-forming additives)
    ANSWER 4 OF 7 CAPLUS COPYRIGHT 2008 ACS on STN
L5
    2000:451479 CAPLUS
AN
    134:86609
DN
ED
    Entered STN: 05 Jul 2000
     Novel design of carbon-rich polymers for 193 nm microlithography:
ΤI
     adamantane-containing cyclopolymers
     Pasini, Dario; Low, Eric; Frechet, Jean M. J.
ΑU
CS
     Department of Chemistry, University of California, Berkeley, CA,
     94720-1460, USA
    Advanced Materials (Weinheim, Germany) (2000), 12(5), 347-351
    CODEN: ADVMEW; ISSN: 0935-9648
PΒ
    Wiley-VCH Verlag GmbH
```

Journal

DT

```
LA
     English
     35-7 (Chemistry of Synthetic High Polymers)
CC
     Section cross-reference(s): 37, 74
AB
     The design and synthesis of carbon-rich copolymers incorporating both
     ter-Bu esters as image able functionalities for chemical
     amplification, and adamantane moieties for etch resistance was
    described.
ST
     adamantane deriv cyclopolymn nanolithog dry etching resistance
     Polymerization catalysts
        (cyclopolymn.; novel design of carbon-rich polymers for 193 nm
        microlithog.: adamantane-containing cyclopolymers)
ΙT
    Resists
        (etching, dry; novel design of carbon-rich polymers for 193 nm
        microlithog.: adamantane-containing cyclopolymers)
ΤТ
     Lithography
        (nano-; novel design of carbon-rich polymers for 193 nm microlithog.:
        adamantane-containing cyclopolymers)
ΙT
     225783-63-1P
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (cyclohexyl-containing; preparation of adamantane-containing
cyclopolymers for 193
        nm microlithog.)
     260357-33-3P
                   260357-34-4P
                                   260357-35-5P
                                                  260357-36-6P
ΤT
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (cyclopolymer; preparation of adamantane-containing cyclopolymers for
193 nm
       microlithoq.)
ΙT
     78-67-1, 2,2'-Azobisisobutyronitrile
     RL: CAT (Catalyst use); USES (Uses)
        (cyclopolymn catalyst; novel design of carbon-rich polymers for 193 nm
        microlithog.: adamantane-containing cyclopolymers)
ΙT
     2589-57-3
     RL: CAT (Catalyst use); USES (Uses)
        (cyclopolymn catalyst; preparation of adamantane-containing
cyclopolymers for
        193 nm microlithog.)
     106-95-6, Allyl bromide, reactions 768-95-6, 1-Adamantanol
     1663-67-8, Malonyl dichloride
                                     53913-96-5, tert-Butyl
     2-(Bromomethyl)acrylate
    RL: RCT (Reactant); RACT (Reactant or reagent)
        (monomer synthesis; preparation of adamantane-containing
cyclopolymers for 193
        nm microlithog.)
                    260357-31-1DP, t7
ΤТ
     173614-51-2P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (monomer synthesis; preparation of adamantane-containing
cyclopolymers for 193
        nm microlithog.)
ΙT
     225783-60-8P
                    260357-32-2P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (monomer; preparation of adamantane-containing cyclopolymers for 193
nm
        microlithog.)
```

```
RE.CNT 34
              THERE ARE 34 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE
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(2) Bizilj, S; Aust J Chem 1985, V38, P1657 CAPLUS
(3) Butler, G; Acc Chem Res 1982, V15, P370 CAPLUS
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L5
    ANSWER 5 OF 7 CAPLUS COPYRIGHT 2008 ACS on STN
ΑN
    1996:444777 CAPLUS
DN
    125:208216
    Entered STN: 27 Jul 1996
ED
ΤI
    Effect of additives in ArF single layer chemical
     amplification photoresist
ΑU
     Suwa, Mitsuhito; Kajita, Toru; Iwanaga, Shin-Ichiro
     Electronic Material Lab., Yokkaichi Res. Lab., Japan Synthetic Rubber
CS
Co.,
     Ltd., Yokkaichi, 510, Japan
     Journal of Photopolymer Science and Technology (1996), 9(3), 489-496
SO
     CODEN: JSTEEW; ISSN: 0914-9244
     Technical Association of Photopolymers, Japan
PΒ
DT
    Journal
LA
    English
CC
     74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
```

Reprographic Processes)

AB This paper describes a new approach to the design of pos.-tone ArF single layer chemical amplification (CA) photoresist. The main issue is the effect of small mol. compds. as additives in methacrylic-based ArF CA photoresist. Three alicyclic compds. with adamantyl moiety and two aromatic compds. with naphthyl moiety were selected

as additives. Their influences on the photoresist properties were examined

and clarified as follows: Transparency of the resist film at 193-nm could be controlled by the loading level and the sorts of additives. Alicyclic additives made the resist film more transparent. Both the photospeed and the contrast of the resist were drastically influenced by the loaded additives. Enhancement of the photospeed was easily achieved. Thermal properties of the resist film could also be affected by additives. However, the effect was generally temperate. The loaded additives could mitigate T-top formation of resist profile due to the control of the inherent dissoln. rate of the resist. Loading the additives would compensate some inherent defects of matrix acrylic polymers and consequently allow considerable latitude in resist design of ArF CA resist. A three component system comprising an acrylic polymer, a photoacid generator, and adamantanecarboxylic acid showed good imaging performance (0.26 μ mL/S, 35mJ/cm2) on KrF exposure.

ST adamantyl naphthyl additive chem amplification photoresist

IT Resists

(photo-, effect of additives in ArF single layer chemical amplification photoresist)

IT 86-55-5, 1-Naphthoic acid 90-15-3, 1-Naphthol 768-95-6, 1-Adamantanol 828-51-3, 1-Adamantanecarboxylic acid 4942-47-6, 1-Adamantane acetic acid

RL: MOA (Modifier or additive use); USES (Uses)
 (effect of additives in ArF single layer chemical
 amplification photoresist)

IT 72145-62-1, tert-Butyl methacrylate-Methacrylic acid-methyl methacrylate copolymer

RL: TEM (Technical or engineered material use); USES (Uses) (effect of additives in ArF single layer chemical amplification photoresist)

IT 78-67-1, 2,2'-Azobisisobutyronitrile

RL: TEM (Technical or engineered material use); USES (Uses) (initiator; effect of additives in ArF single layer chemical amplification photoresist)

IT 66003-78-9, Triphenylsulfonium trifluoromethanesulfonate 160481-39-0 RL: TEM (Technical or engineered material use); USES (Uses) (photoacid generator; effect of additives in ArF single layer chemical amplification photoresist)

- L5 ANSWER 6 OF 7 CAPLUS COPYRIGHT 2008 ACS on STN
- AN 1993:115738 CAPLUS
- DN 118:115738
- ED Entered STN: 19 Mar 1993
- TI Voltammetric study on a condensed monolayer of a long alkyl cyclodextrin derivative as a channel mimetic sensing membrane
- AU Odashima, Kazunori; Kotato, Minoru; Sugawara, Masao; Umezawa, Yoshio
- CS Fac. Sci., Hokkaido Univ., Sapporo, 060, Japan

```
Analytical Chemistry (1993), 65(7), 927-36
SO
    CODEN: ANCHAM; ISSN: 0003-2700
DT
    Journal
LA
    English
CC
    79-2 (Inorganic Analytical Chemistry)
     Section cross-reference(s): 66, 72, 80
    For a fundamental study on the development of signal-amplifying
AB
     chemical sensors that mimic biol. ion channels, a control of membrane
    permeability based on the blocking of an intramol. channel by host-quest
    complexation was studied for a condensed monolayer of a long alkyl
derivative
     of \beta-cyclodextrin having a channel-like structure
     (6A, 6B, 6C, 6D, 6E, 6F, 6G-heptadeoxy-6A, 6B, 6C, 6D, 6E, 6F, 6G-
     heptakis(dodecylthio)-\beta-cyclodextrin tetradecaacetate).
                                                              To obtain
     exptl. evidence for such a mode of permeability control, an approach
based
     on horizontal touch cyclic voltammetry was carried out for this condensed
     monolayer, which was formed at the air/H2O interface by applying a
     controlled high surface pressure to minimize the permeability through the
     intermol. voids between the membranous cyclodextrin mols. By comparing
     the permeabilities for 3 kinds of electroactive markers that differ in
the
     steric bulkiness and/or hydrophobicity, rigid evidence was obtained for
     the ability of this cyclodextrin derivative to function as an intramol.
     channel. The permeability of this channel for a sterically permeable
    marker (p-quinone) is able to be controlled by blocking the channel with
а
    quest mol. By using this condensed monolayer, the selectivity of
    permeability inhibition was examined for several organic quests.
mol.
     response ratio as a measure of signal transduction efficiency was up to
     10.4.
ST
     signal amplifying chem sensor cyclodextrin membrane;
     long alkyl cyclodextrin deriv sensing membrane; dodecylthiocyclodextrin
     tetradecaacetate based sensing membrane
ΙT
        (chemical, condensed cyclodextrin derivative monolayer as channel
        mimetic sensing membrane, preparation and voltammetric study of)
ΙT
     Electrodes
        (membrane, channel mimetic, condensed cyclodextrin derivative
monolayer as,
        preparation and voltammetric study of)
     110577-05-4
ΤТ
     RL: ANST (Analytical study)
        (condensed monolayer of, as channel mimetic sensing membrane,
preparation
        and voltammetric study of)
IΤ
     58-61-7, Adenosine, miscellaneous
                                        65-46-3, Cytidine
                                                              100-51-6, Benzyl
                              108-93-0, Cyclohexanol, miscellaneous
     alcohol, miscellaneous
     768-95-6, 1-Adamantanol
     RL: MSC (Miscellaneous)
        (guest, cyclic voltammogram area decrease of quinone in presence of
        condensed cyclodextrin derivative monolayer in relation to)
ΙT
     106-51-4, p-Quinone, analysis 15317-76-7 17456-18-7, Tetrapotassium
```

octacyanomolybdate

```
RL: ANST (Analytical study)
        (horizontal touch cyclic voltammetry of, using highly oriented
        pyrolytic graphite working electrode with/without condensed
        cyclodextrin derivative monolayer, comparison of)
    ANSWER 7 OF 7 CAPLUS COPYRIGHT 2008 ACS on STN
L5
    1990:97858 CAPLUS
DN
    112:97858
    Entered STN: 18 Mar 1990
ED
TΙ
    On the mechanism of the Gif and Gif-Orsay systems for the selective
     substitution of saturated hydrocarbons
ΑU
     Barton, Derek H. R.; Halley, Frank; Ozbalik, Nubar; Young, Esme;
     Balavoine, Gilbert; Gref, Auroro; Boivin, Jean
     Dep. Chem., Texas A and M Univ., College Station, TX, 77843, USA
CS
    New Journal of Chemistry (1989), 13(3), 177-82
SO
    CODEN: NJCHE5; ISSN: 1144-0546
DT
    Journal
LA
    English
CC
     22-7 (Physical Organic Chemistry)
     Section cross-reference(s): 29
     CASREACT 112:97858
OS
AB
     The usual chemoselective behavior of the Gif and Gif-Orsay
     systems for the selective oxidation of saturated hydrocarbons is briefly
     reviewed. The Gif system also phenylselenates saturated hydrocarbons,
using
     iron powder as reductant with di-Ph diselenide and oxygen as reactants.
     Recent studies have confirmed the role of the iron-carbon \sigma-bond and
     have shown that the reactive species is a Fev-oxenoid. The mechanism
     originally proposed can now be amplified.
ST
    Gif system mechanism; substitution satd hydrocarbon Gif Orsay
ΙT
    Oxidation catalysts
     Redox reaction catalysts
        (homogeneous iron based, for saturated hydrocarbons and Gif system,
        mechanism with)
ΙT
    Alcohols, preparation
     Ketones, preparation
     RL: PREP (Preparation)
        (in Gif and Gif-Orsay systems, mechanism of)
ΙT
    Regiochemistry
        (of Gif type oxidns. of adamantane)
ΙT
     Substitution reaction
        (of saturated hydrocarbons in Gif and Gif-Orsay systems, mechanism of)
ΤТ
    Oxidation
     Redox reaction
        (of saturated hydrocarbons in Gif system, mechanism of)
ΤТ
     Solvent effect
        (on Gif oxidns.)
IΤ
     Cycloalkanes
     Hydrocarbons, reactions
    RL: RCT (Reactant); RACT (Reactant or reagent)
        (oxidation of, in Gif and Gif-Orsay systems, mechanism of)
ΙT
    Oxidation, electrochemical
        (Gif-Orsay, of saturated hydrocarbon, mechanism of)
ΙT
     Bond formation
```

(carbon-iron, σ , in Gif systems)

```
ΙT
    Redox reaction
        (electrochem., Gif-Orsay, of saturated hydrocarbon, mechanism of)
ΙT
     Oxidation catalysts
     Redox reaction catalysts
        (electrochem., iron based, for saturated hydrocarbons in Gif-Orsay
system,
       mechanism with)
     64-19-7P, Acetic acid, preparation 110-86-1P, Pyridine, preparation
ΤТ
     RL: PREP (Preparation)
        (Gif oxidns. in presence of, mechanism of)
ΙT
     7705-08-0, Ferric chloride, uses and miscellaneous 15138-92-8
    RL: CAT (Catalyst use); USES (Uses)
        (catalysts, for Gif systems, mechanism with)
     108-93-0P, Cyclohexanol, preparation 700-57-2P, 2-Adamantanol
ΤТ
     700-58-3P, Adamantanone 768-95-6P, 1-Adamantanol
     RL: FORM (Formation, nonpreparative); PREP (Preparation)
        (formation of, in Gif system, catalysts for)
ΤT
     108-94-1P, Cyclohexanone, preparation
     RL: FORM (Formation, nonpreparative); PREP (Preparation)
        (formation of, in Gif type oxidns., catalysts for)
ΙT
     10058-23-8
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (oxidation by, of saturated alkanes in Gif type system, mechanism
with)
ΙT
    7722-84-1, Hydrogen peroxide, reactions 12030-88-5, Potassium
superoxide
     13718-66-6
    RL: RCT (Reactant); RACT (Reactant or reagent)
        (oxidation by, of saturated hydrocarbons in Gif type systems,
mechanism with)
    7646-93-7
ΙT
    RL: PRP (Properties)
        (oxidation of saturated hydrocarbons in Gif type system containing,
mechanism
        with)
ΙT
     7778-80-5, Potassium sulfate, reactions
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (oxidation of saturated hydrocarbons in Gif type system containing,
mechanism
        with)
ΤТ
     281-23-2, Adamantane
    RL: RCT (Reactant); RACT (Reactant or reagent)
        (oxidation of, by Gif type systems, mechanism and regioselectivity of)
ΤТ
     110-82-7, Cyclohexane, reactions
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (oxidation of, in Gif type systems, mechanism of)
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COST IN U.S. DOLLARS
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                                                                  30.88
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                                                 SINCE FILE
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ENTRY

SESSION

1 95 71 6

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FOR 10/553083 by Cynthia Hamilton
             0 768-95-6
                (768(W)95(W)6)
             0 768-95-6/CRN
           146 CHEM?
             0 AMPLI?
L7
             0 L4 NOT L5
=> S L4 NOT CHEM? AMPLI?
'CRN' IS NOT A VALID FIELD CODE
             0 768
             1 95
            71 6
             0 768-95-6
                (768(W)95(W)6)
             0 768-95-6/CRN
             9 PHOTO?
           146 CHEM?
             0 AMPLI?
             0 CHEM? AMPLI?
                (CHEM?(W)AMPLI?)
L8
             0 L4 NOT CHEM? AMPLI?
=> S L4 NOT CHEM? AND AMPLI?
'CRN' IS NOT A VALID FIELD CODE
             0 768
             1 95
            71 6
             0 768-95-6
                (768(W)95(W)6)
             0 768-95-6/CRN
             9 PHOTO?
           146 CHEM?
             0 AMPLI?
L9
             0 L4 NOT CHEM? AND AMPLI?
=> D HIS
     (FILE 'HOME' ENTERED AT 16:10:07 ON 14 FEB 2008)
     FILE 'REGISTRY' ENTERED AT 16:10:26 ON 14 FEB 2008
            1 S 768-95-6
L1
            127 S 768-95-6/CRN
L2.
     FILE 'CAPLUS' ENTERED AT 16:10:54 ON 14 FEB 2008
           1717 S L1 OR L2
L3
            130 S L3 AND PHOTO?
L4
              7 S L3 AND CHEM? AND AMPLI?
L5
     FILE 'STNGUIDE' ENTERED AT 16:12:00 ON 14 FEB 2008
L6
              0 S L4 NOT L5
L7
              0 S L4 NOT L5
L8
              0 S L4 NOT CHEM? AMPLI?
L9
              0 S L4 NOT CHEM? AND AMPLI?
=> FILE CAPLUS
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=> S L4

1552780 PHOTO?

L10 130 L3 AND PHOTO?

=> S L4 NOT L5

L11 126 L4 NOT L5

=> S L11 AND (ACETAL OR KETAL)

51030 ACETAL 10150 KETAL

L12 1 L11 AND (ACETAL OR KETAL)

=> D

L12 ANSWER 1 OF 1 CAPLUS COPYRIGHT 2008 ACS on STN

AN 1992:20491 CAPLUS

DN 116:20491

TI Photochemistry of phenyl thioethers and phenyl selenoethers. Radical vs. ionic behavior

- AU Kropp, Paul J.; Fryxell, Glen E.; Tubergen, Mark W.; Hager, Michael W.; Harris, G. Davis, Jr.; McDermott, T. Paul, Jr.; Tornero-Velez, Rogelio
- CS Dep. Chem., Univ. North Carolina, Chapel Hill, NC, 27599-3290, USA
- SO Journal of the American Chemical Society (1991), 113(19), 7300-10

CODEN: JACSAT; ISSN: 0002-7863 DT Journal LA English CASREACT 116:20491 OS => D ALL L12 ANSWER 1 OF 1 CAPLUS COPYRIGHT 2008 ACS on STN 1992:20491 CAPLUS DN 116:20491 ED Entered STN: 24 Jan 1992 Photochemistry of phenyl thioethers and phenyl selenoethers. ΤТ Radical vs. ionic behavior ΑU Kropp, Paul J.; Fryxell, Glen E.; Tubergen, Mark W.; Hager, Michael W.; Harris, G. Davis, Jr.; McDermott, T. Paul, Jr.; Tornero-Velez, Rogelio Dep. Chem., Univ. North Carolina, Chapel Hill, NC, 27599-3290, USA CS SO Journal of the American Chemical Society (1991), 113(19), 7300-10 CODEN: JACSAT; ISSN: 0002-7863 DTJournal LA English CC 22-4 (Physical Organic Chemistry) CASREACT 116:20491 OS AΒ Ph thio- and Ph selenoethers displayed competing radical and ionic photobehavior on irradiation in solution, via a mechanism thought to involve initial homolytic cleavage of the alkyl C-S or C-Se bond followed by electron transfer within the resulting radical pair cage. These are the first examples of ionic photobehavior to be recognized for the C-SAr and C-SeAr chromophores. The electronegatively substituted pentafluorophenyl analogs displayed enhanced ionic photobehavior . By contrast, a 4-methoxyphenyl derivative exhibited almost exclusively radical behavior. A sulfoxide displayed principally radical behavior, accompanied by epimerization at sulfur. The quantum yields for the disappearance of the 2-norbornyl thioethers were 0.53-0.64 in solution and rose to 0.89-0.95 in the presence of suspended fumed silica, which involved nucleophilic trapping by surface silanol groups to afford covalently bound material that afforded a chloride on treatment with SOC12. Irradiation of Ph thioethers, Ph selenoether or C6H5SH in allyl alc. solution afforded an acetal , apparently via isomerization of some

of the solvent to a propanal followed by acetalization. Irradiation of alc.

solns. of aldehydes containing C6H5SH is a useful means of generating acetals

under neutral conditions.

- thioether phenyl photochem radical mechanism; selenoether phenyl photolysis ionic mechanism
- ΙT Sulfides, reactions

RL: RCT (Reactant); RACT (Reactant or reagent)

(Ph, photolysis of, ionic vs. radical mechanism of)

ΙT Photolysis

(of Ph thio- or selenoethers, ionic vs. radical mechanism of)

ΙT Substituent effect

(on photolysis mechanism of Ph thio- or selenoethers)

```
ΙT
     Solvent effect
        (on photolysis of Ph thio- or selenoethers)
ΙT
     Acetals
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (photochem. preparation of, under neutral conditions)
ΙT
     Ethers, reactions
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (Ph, seleno, photolysis of, ionic vs. radical mechanism of)
     Electron exchange and Charge transfer
ΤТ
        (photochem., in photolysis of Ph thio- or
        selenoethers)
ΙT
     1666-13-3, Diphenyl diselenide
     RL: PROC (Process)
        (conversion of, to Ph selenotricyclodecane)
ΙT
     110-87-2
     RL: PROC (Process)
        (conversion of, to Ph tetrahydropyranyl sulfide)
ΤТ
     25139-43-9
     RL: PROC (Process)
        (conversion of, to Ph thioether derivs.)
ΙT
     628-92-2, Cycloheptene 768-95-6, Tricyclo[3.3.1.13,7]decan-1-ol
     2534-77-2
               132802-42-7
     RL: PROC (Process)
        (conversion of, to Ph thioethers)
ΙT
     696-63-9, 4-Methoxythiophenol 2973-86-6
     RL: PROC (Process)
        (conversion of, to norbornylphenyl sulfide derivative)
ΙT
     34837-55-3, Benzeneselenenyl bromide
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (coupling of, with bromonorbornane in presence of magnesium)
ΙT
     7631-86-9, Silica, uses
     RL: PRP (Properties)
        (effect of, on photolysis of Ph tetrahydropyranyl sulfide in
       presence allyl alc.)
ΙT
     67-56-1, Methanol, reactions
                                  107-18-6, Allyl alcohol, reactions
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (photochem. reaction of, with Ph thioethers, mechanism of)
ΙT
     58652-54-3P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (preparation and conversion of, to Ph thioethers)
     24584-22-3P
ΙT
                  41327-09-7P
                                 135394-86-4P
                                                135394-87-5P
                                                               135394-88-6P
                  135501-25-6P
     135394-89-7P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (preparation and photolysis of)
                  75480-69-2P 88459-01-2P
ΤT
     20965-36-0P
                                              128337-02-0P
                                                              135394-82-0P
     135394-84-2P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (preparation and photolysis of, mechanism of)
     123-38-6P, Propanal, preparation 142-68-7P 279-19-6P,
                                  279-23-2P, Bicyclo[2.2.1]heptane
     Tricyclo[2.2.1.02,6]heptane
     281-23-2P, Tricyclo[3.3.1.13,7]decane 765-91-3P
                                                         780-68-7P
     3732-31-8P, 1,1'-Bitricyclo[3.3.1.13,7]decane
                                                     4203-49-0P 6221-74-5P
     6581-66-4P 10395-53-6P
                               10501-16-3P
                                             18947-78-9P, 2,2'-
```

Bibicyclo[2.2.1]heptane 19066-23-0P 20615-53-6P 24536-40-1P, 3-(Phenylthio)-1-propanol 135394-83-1P 135394-85-3P 135394-90-0P 135501-26-7P 135501-27-8P 135501-28-9P RL: SPN (Synthetic preparation); PREP (Preparation)

L: SPN (Synthetic preparation); PREP (Preparation (preparation of)

IT 108-98-5, Thiophenol, reactions 771-62-0, Pentafluorothiophenol RL: RCT (Reactant); RACT (Reactant or reagent)

(reaction of, with adamantyltosylate)

IT 106-95-6, 3-Bromopropene, reactions

RL: RCT (Reactant); RACT (Reactant or reagent) (reaction of, with tricyclodecanol, propenyloxytricyclodecane by)

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